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DEVICE FOR INTRACRANIAL
NEUROMONITORING****Publication Classification**(51) **Int. Cl.***A61B 5/00* (2006.01)*A61B 5/1486* (2006.01)*A61B 5/145* (2006.01)*A61B 5/01* (2006.01)*A61B 5/03* (2006.01)(52) **U.S. Cl.**CPC *A61B 5/6852* (2013.01); *A61B 5/01*
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(2013.01); *A61B 2562/125* (2013.01); *A61B*
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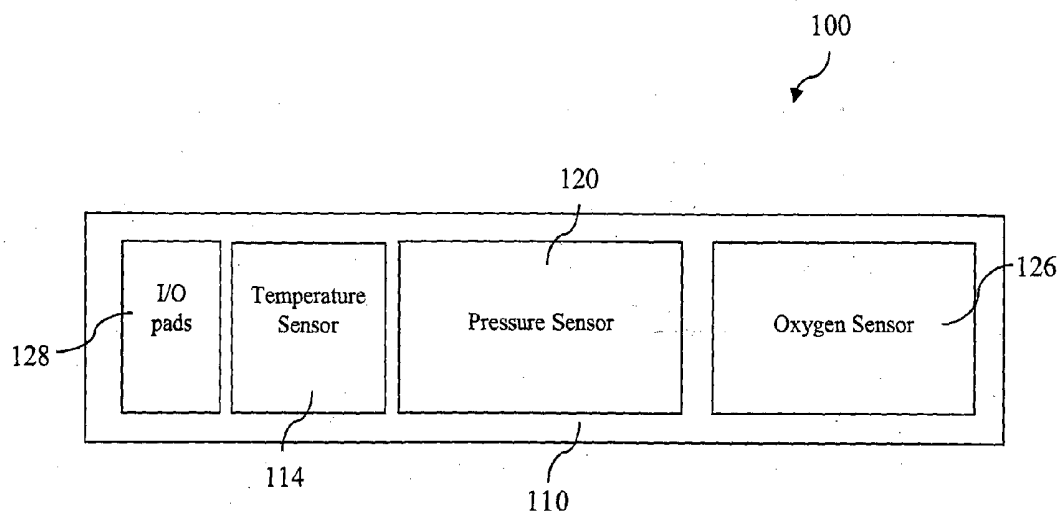
(2) Date: **Dec. 10, 2015**(30) **Foreign Application Priority Data**

Jun. 12, 2013 (SG) 201304550-5

(57)

ABSTRACT

There is provided a monolithically integrated multimodal sensor device for intracranial neuromonitoring, the sensor device including: a single substrate; a temperature sensor formed on a first portion of the single substrate for detecting temperature; a pressure sensor formed on a second portion of the single substrate for detecting intracranial pressure; and an oxygen sensor formed on a third portion of the single substrate for detecting oxygen concentration. In particular, sensing portions of the temperature sensor, the oxygen sensor and the pressure sensor, respectively, are formed at different layers of the sensor device. There is also provided an integrated multimodal sensor system incorporating the sensor device and the associated methods of fabrication.



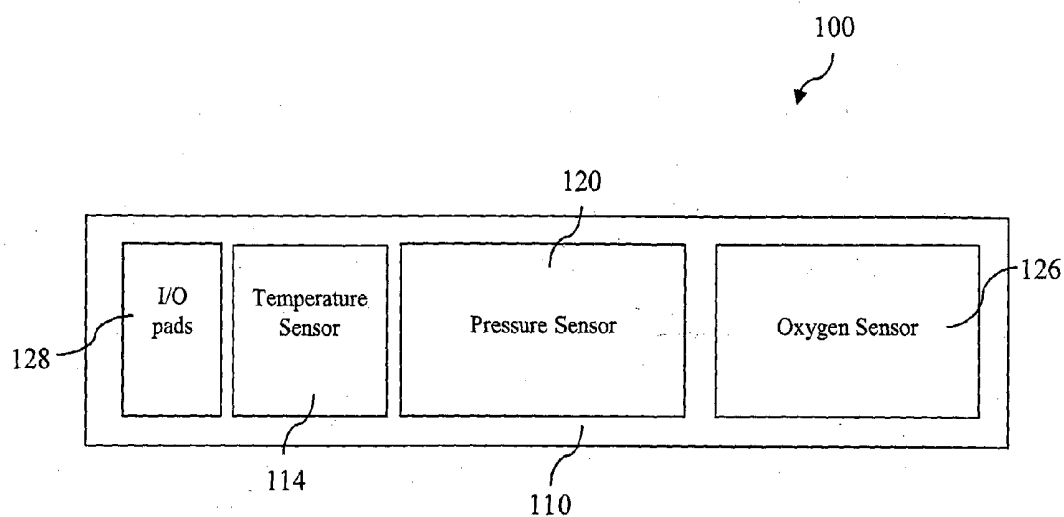


FIG. 1A

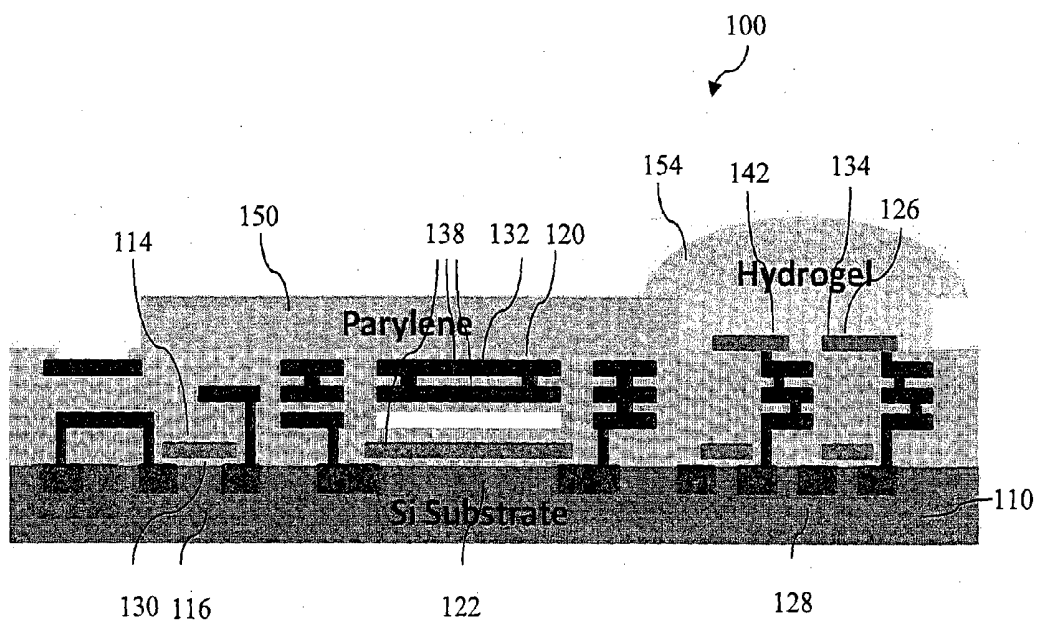


FIG. 1B

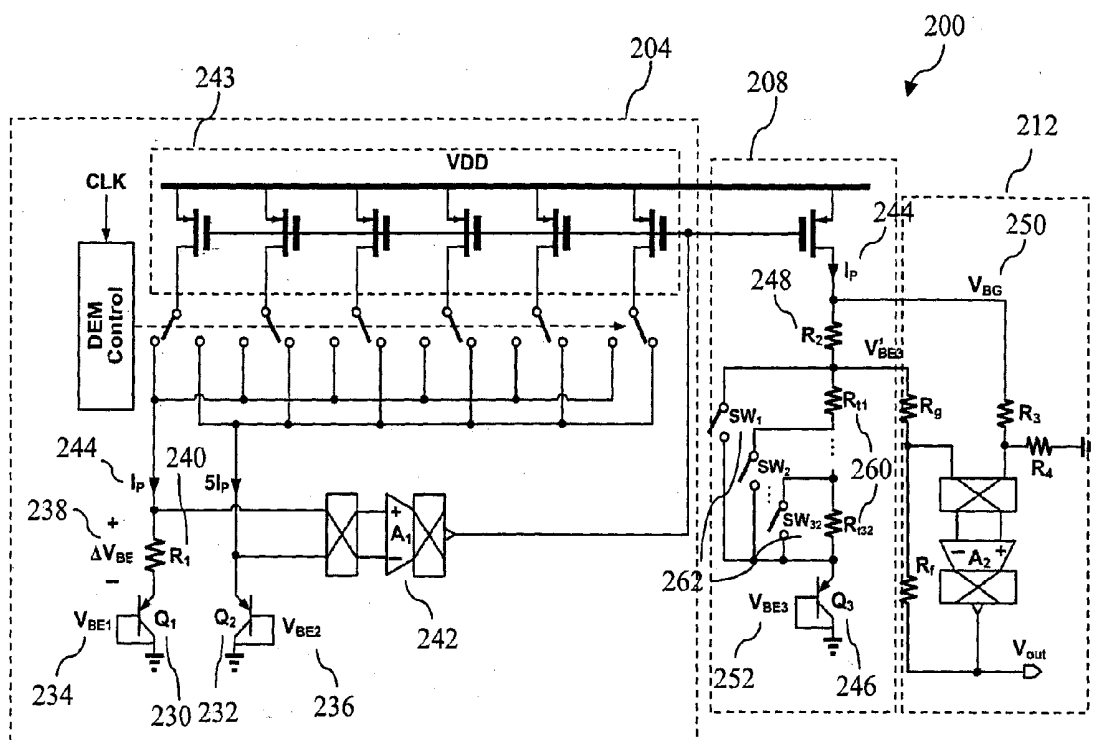


FIG. 2

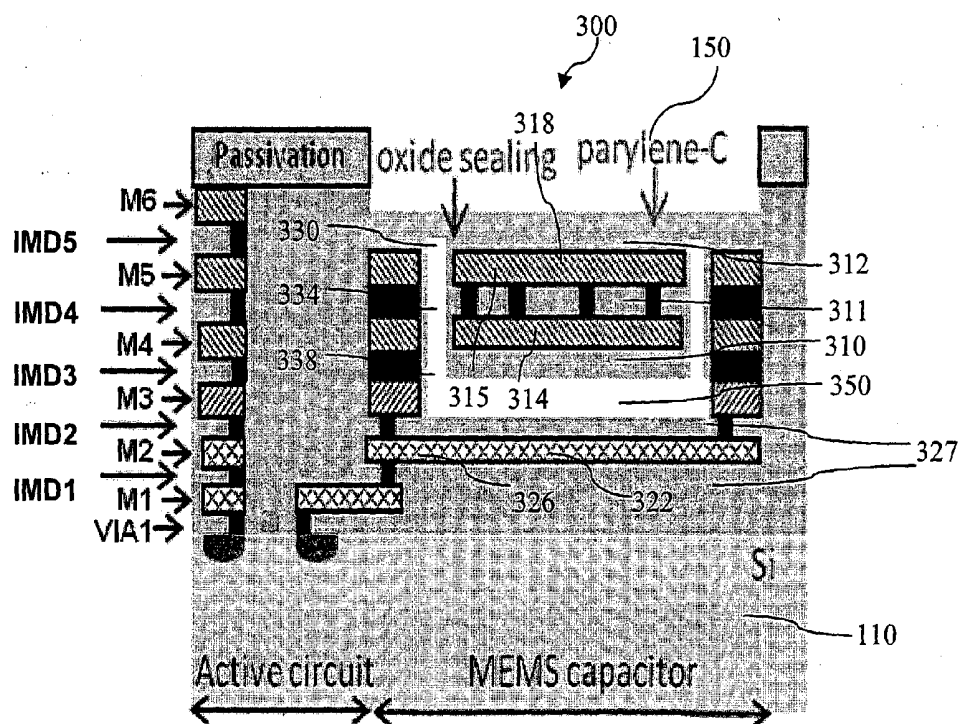


FIG. 3A

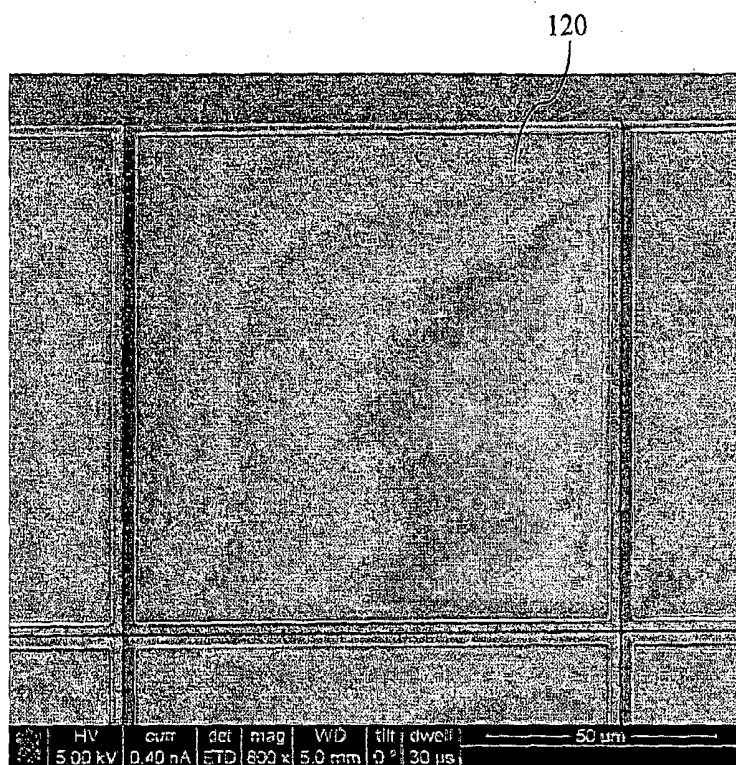


FIG. 3B

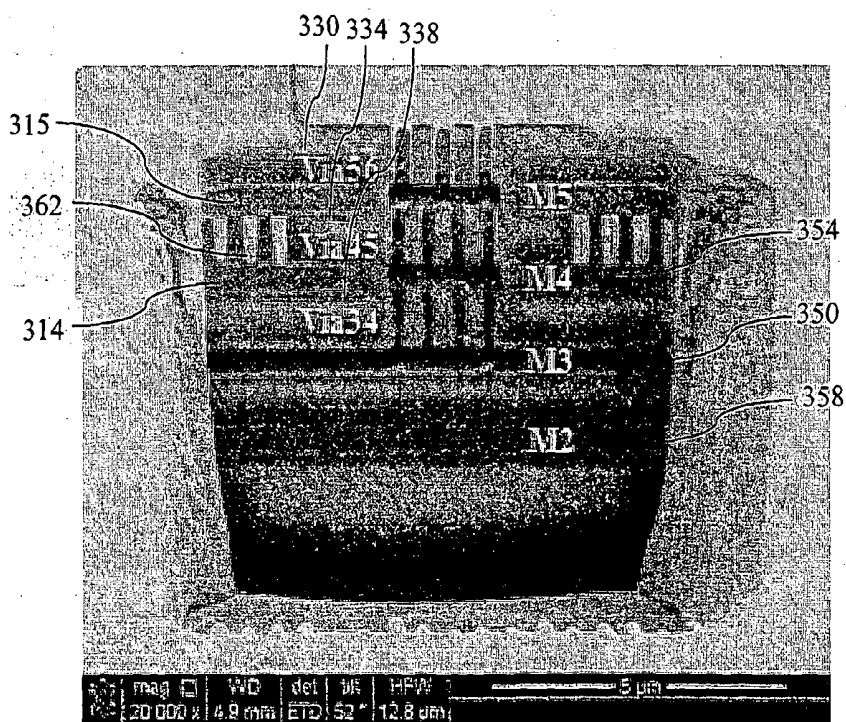


FIG. 3C

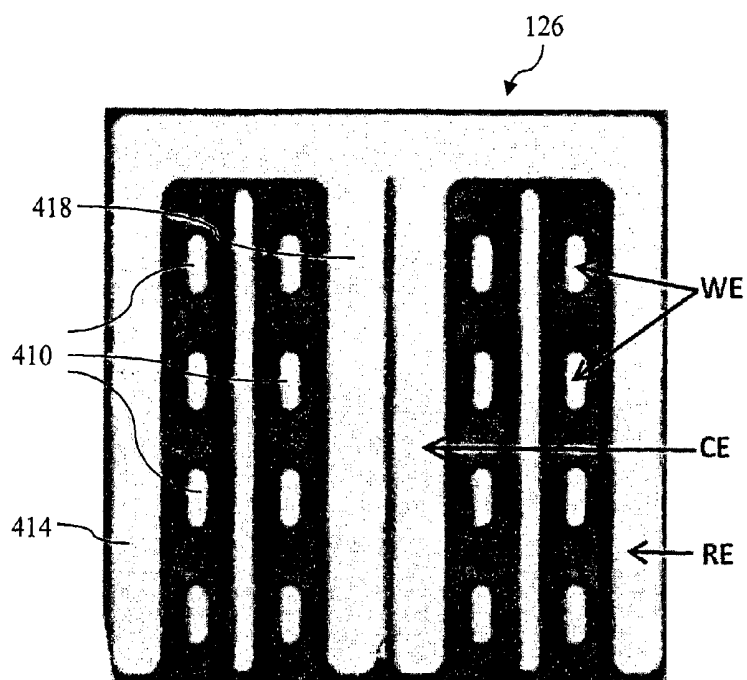


FIG. 4

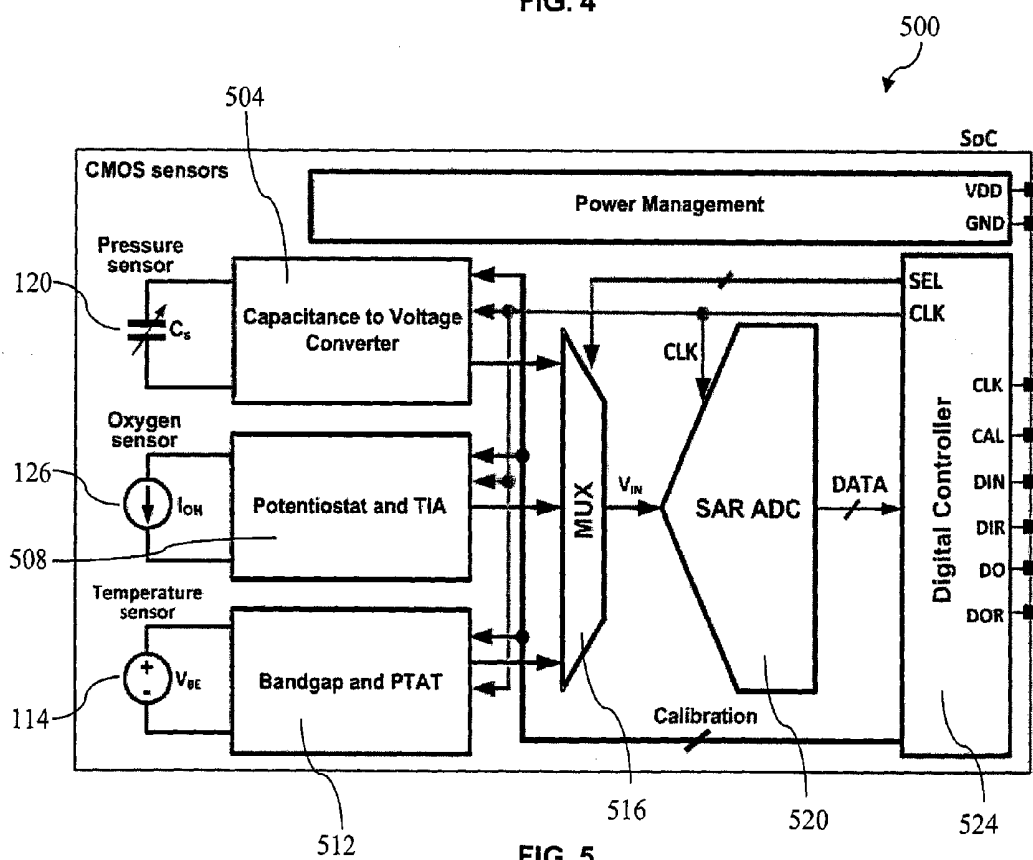


FIG. 5

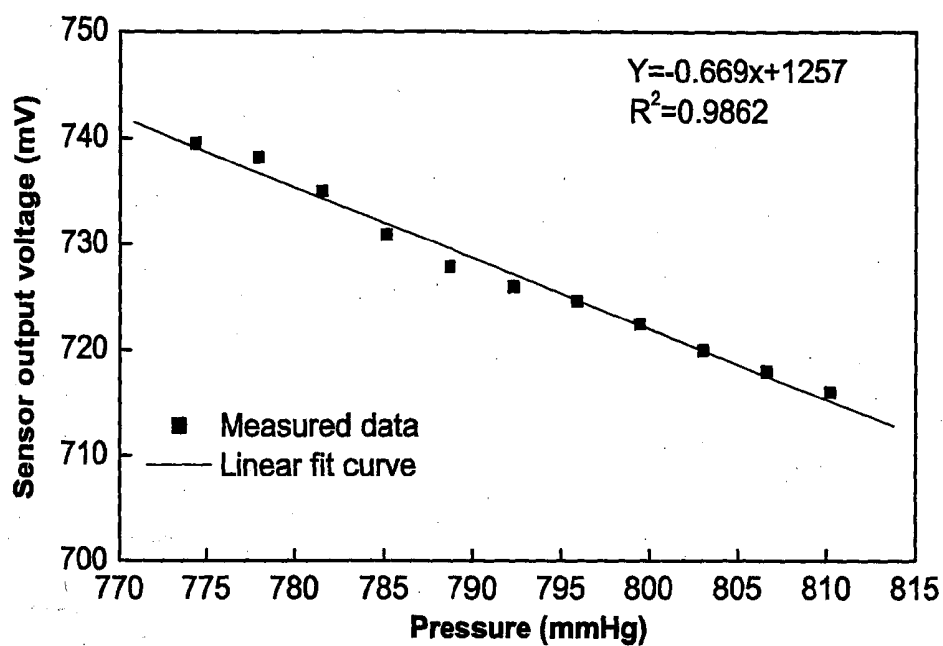


FIG. 6A

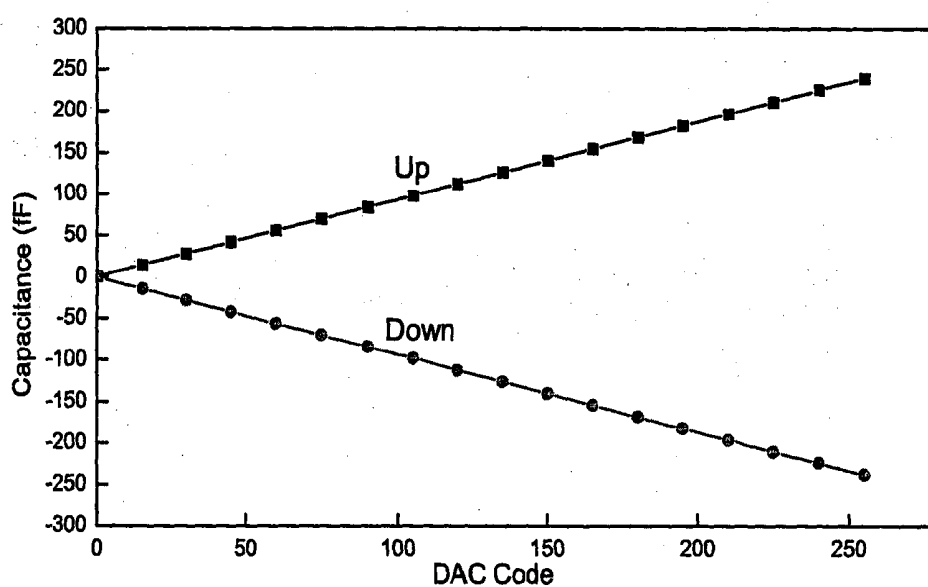


FIG. 6B

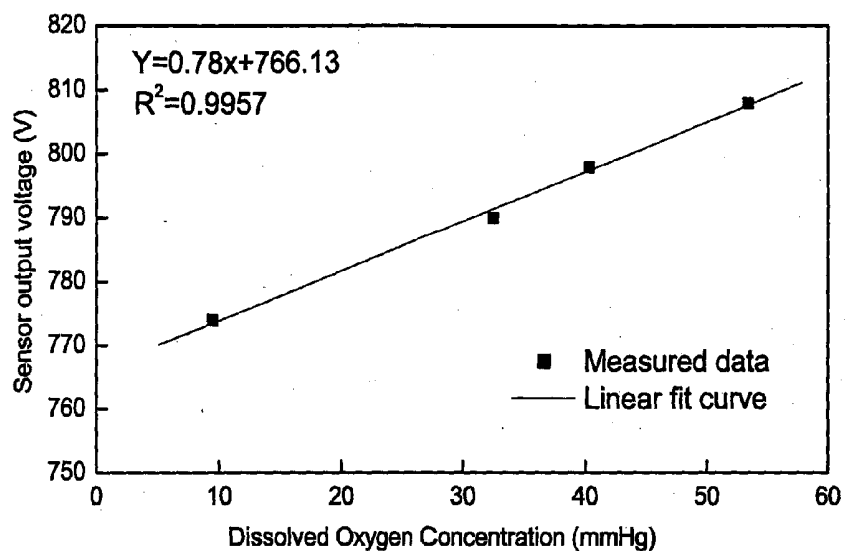


FIG. 7A

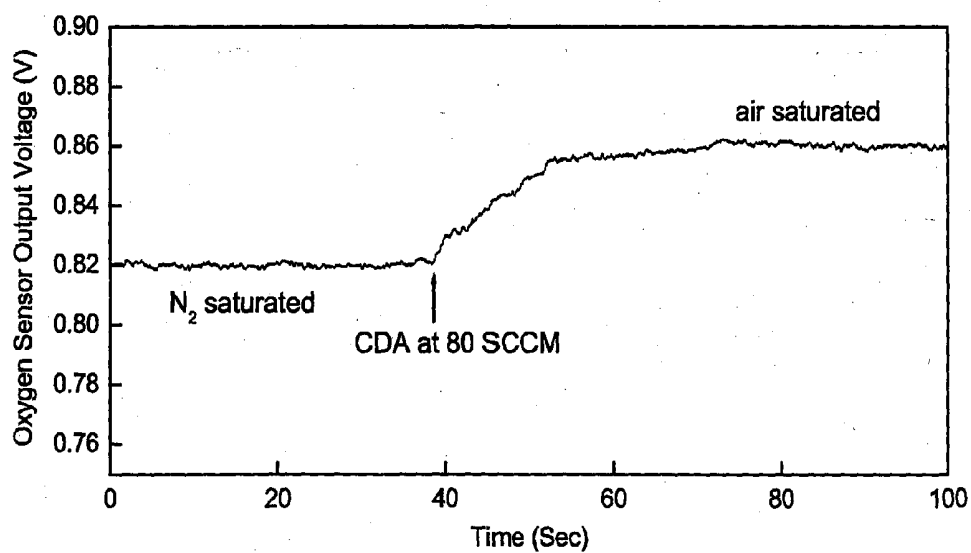
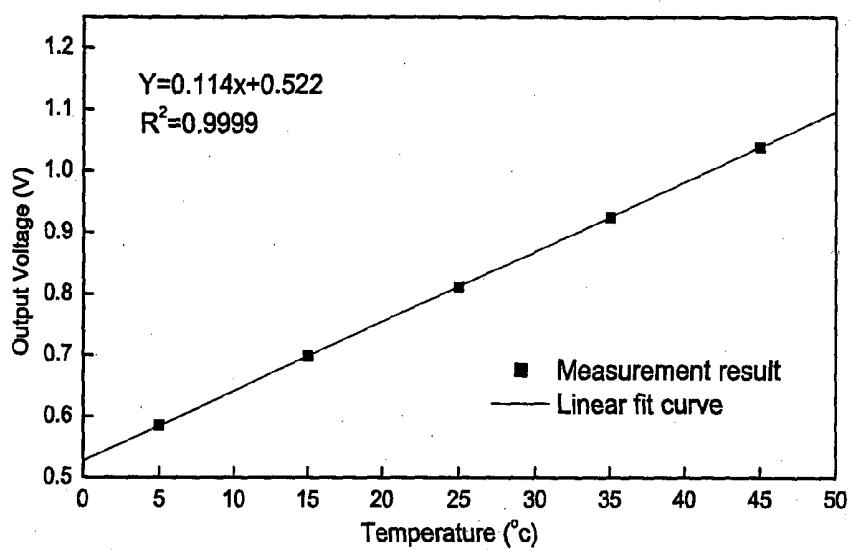
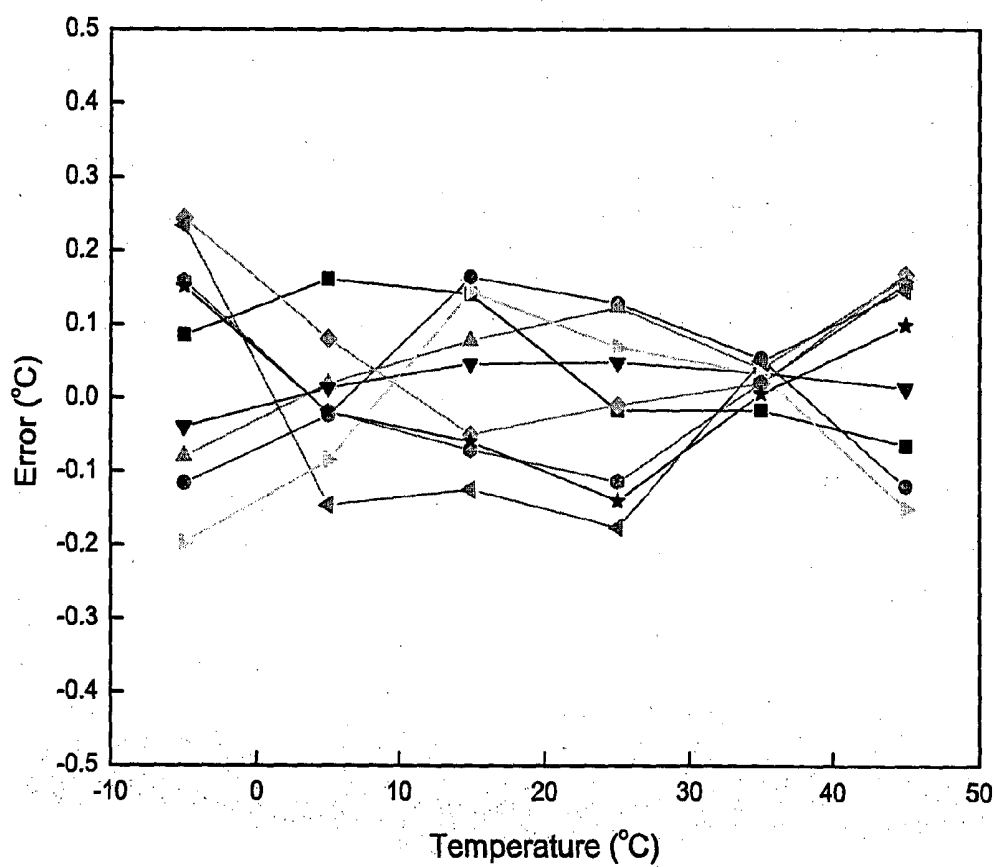


FIG. 7B

Measured V_{OUT} Versus Temperature**FIG. 8A****FIG. 8B**

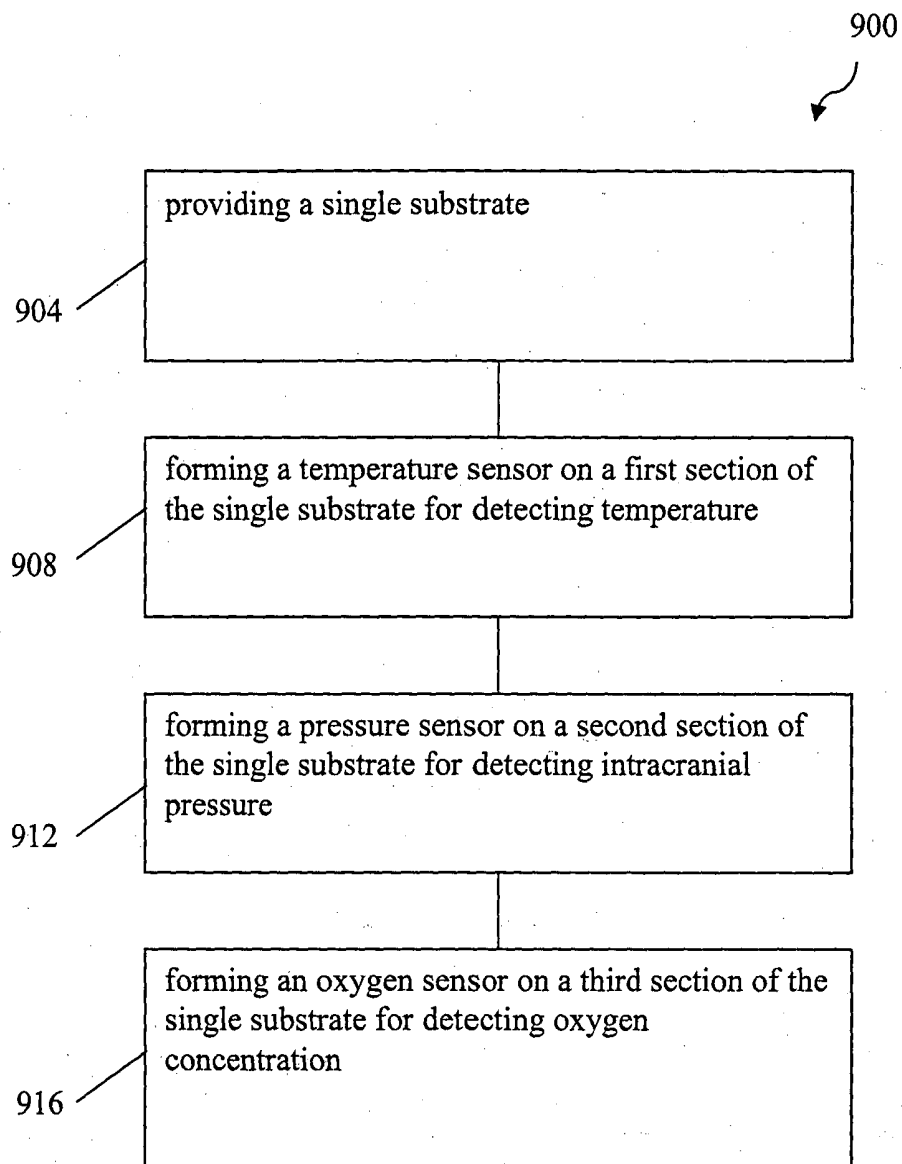


FIG. 9



FIG. 10A

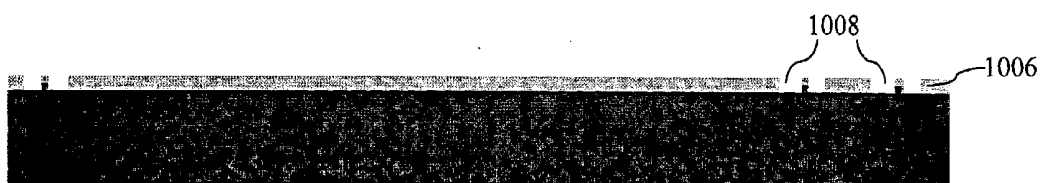


FIG. 10B



FIG. 10C



FIG. 10D



FIG. 10E

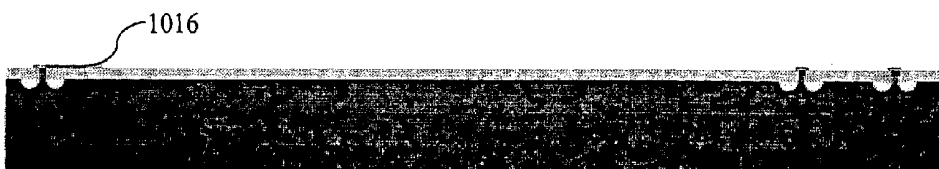


FIG. 10F

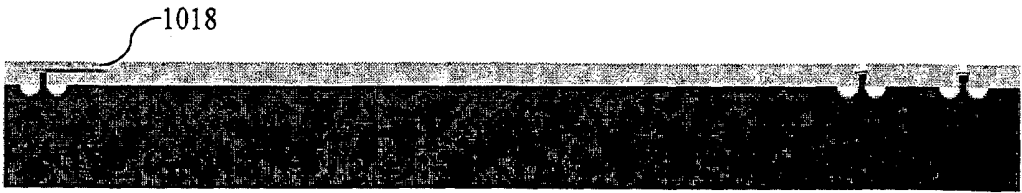


FIG. 10G

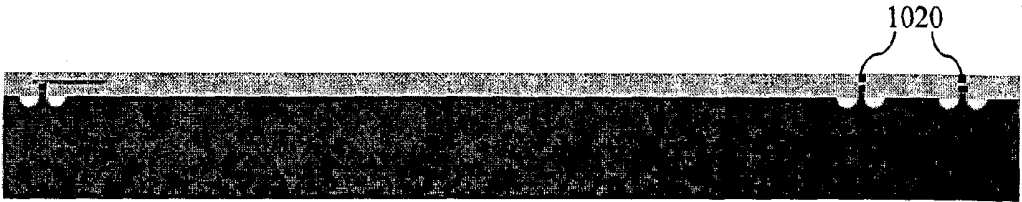


FIG. 10H

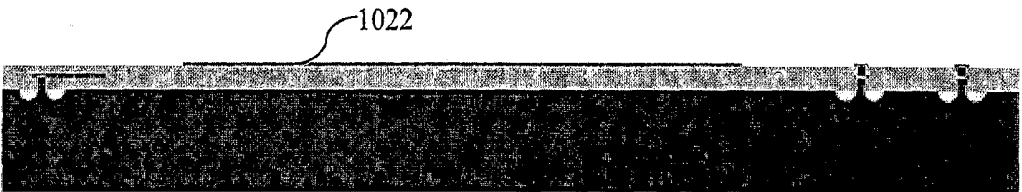


FIG. 10I

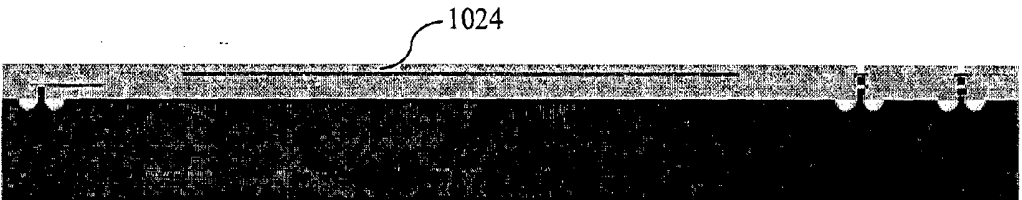


FIG. 10J

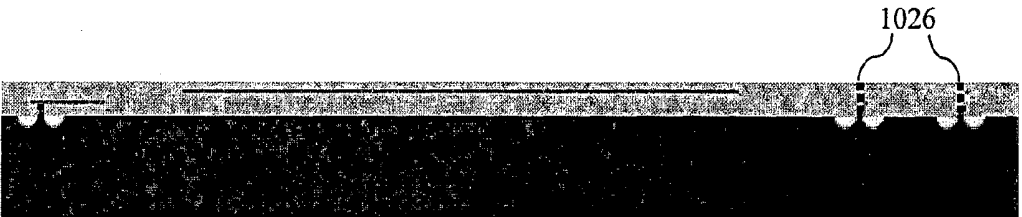


FIG. 10K

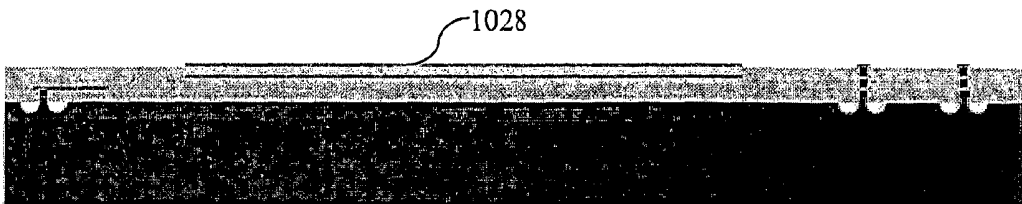


FIG. 10L

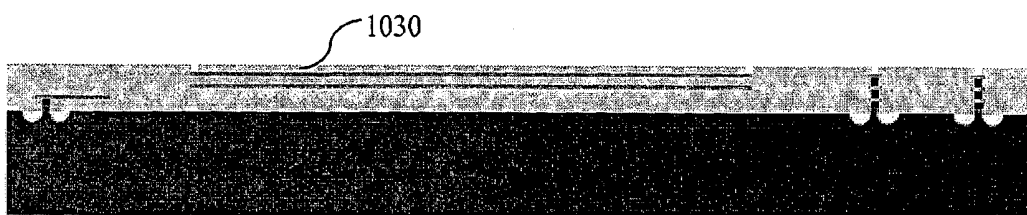


FIG. 10M

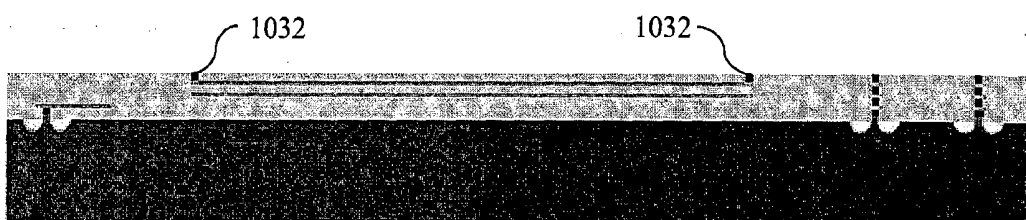


FIG. 10N

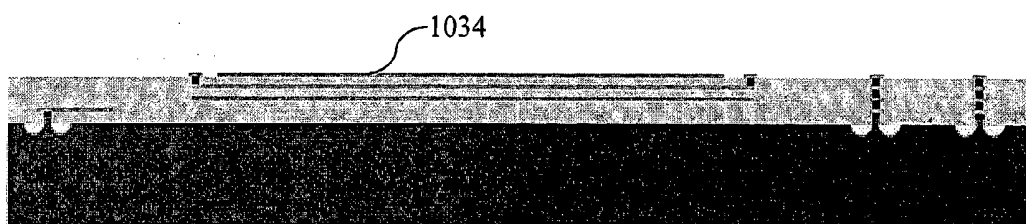


FIG. 10O

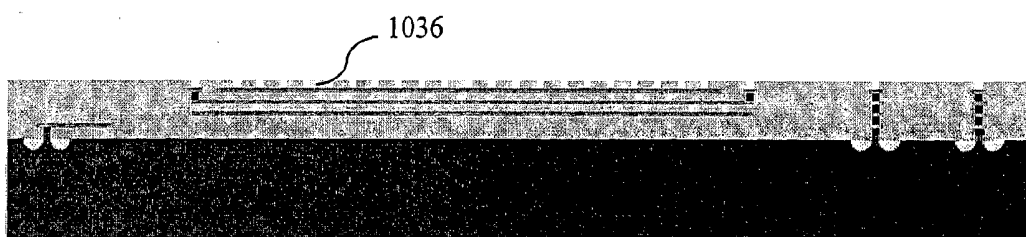


FIG. 10P



FIG. 10Q

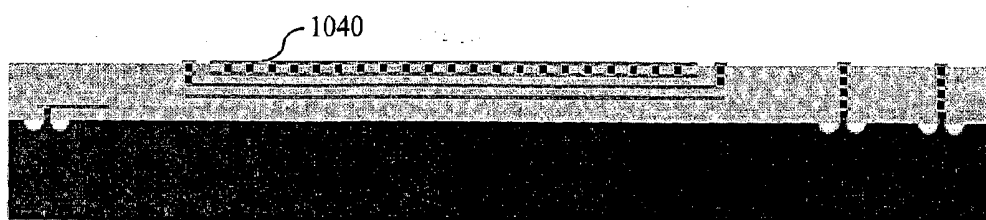


FIG. 10R

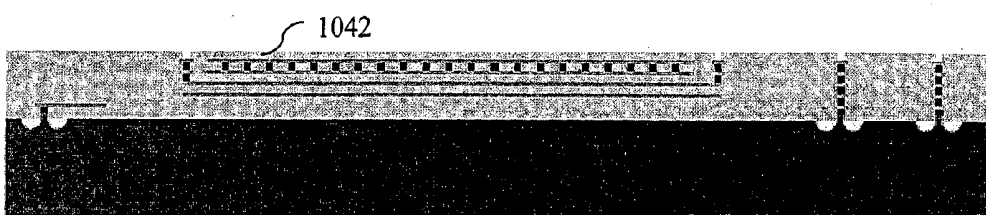


FIG. 10S

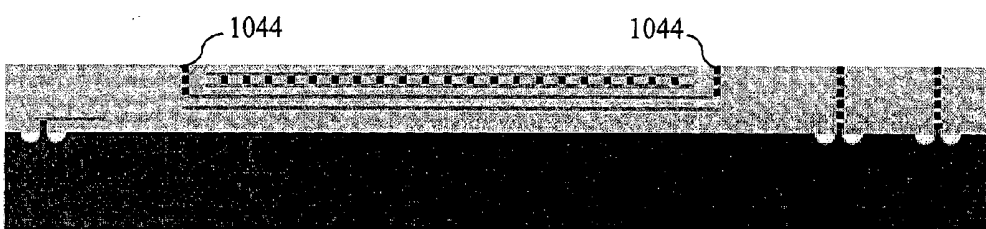


FIG. 10T

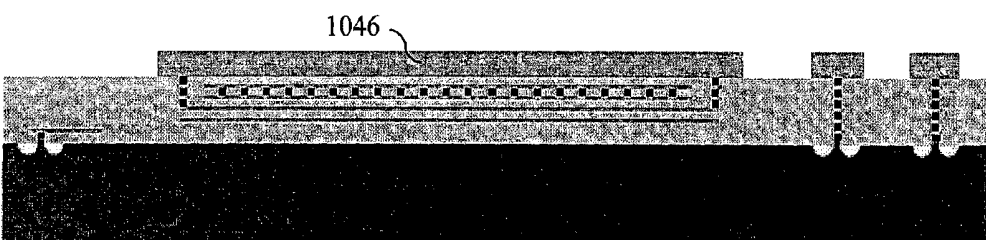


FIG. 10U

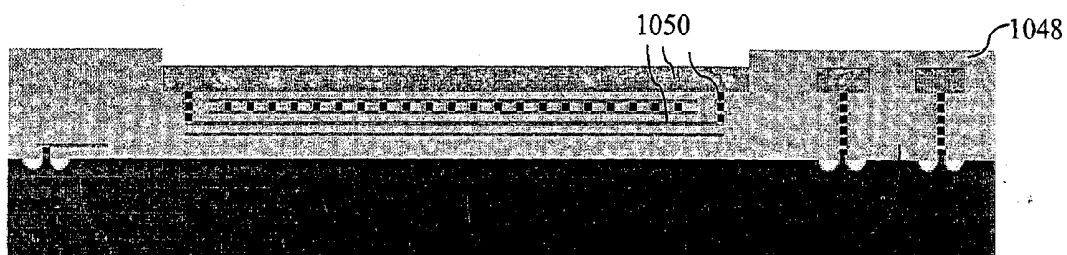


FIG. 10V

114

120

126

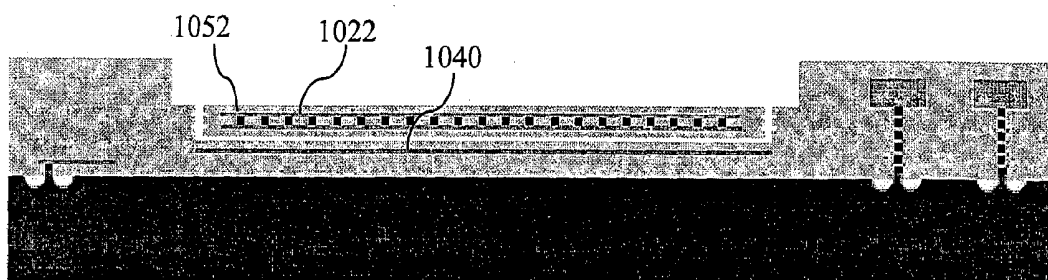


FIG. 10W

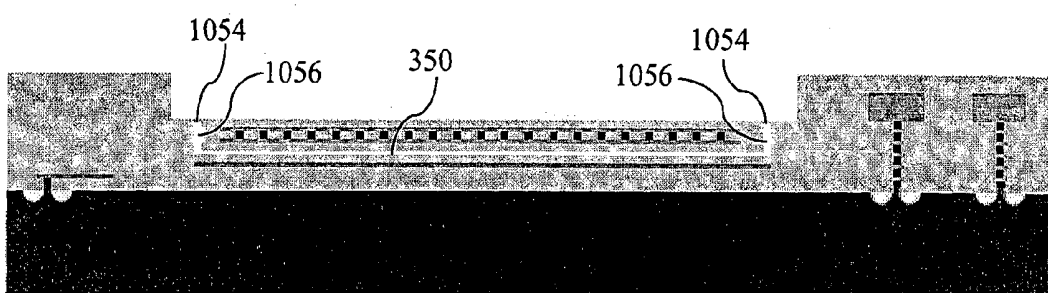


FIG. 10X

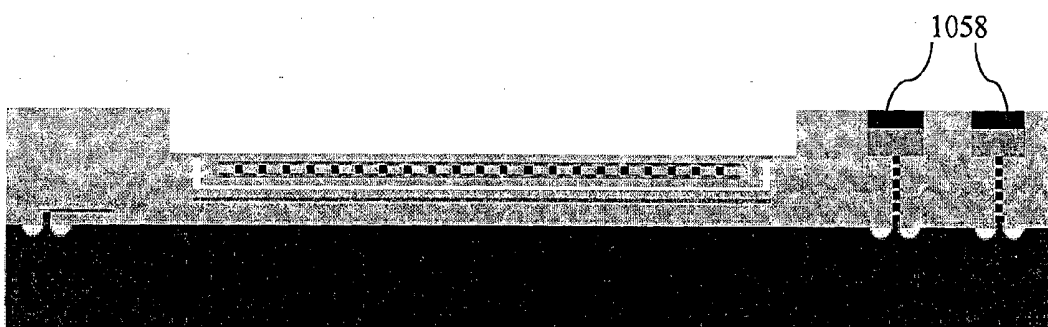


FIG. 10Y

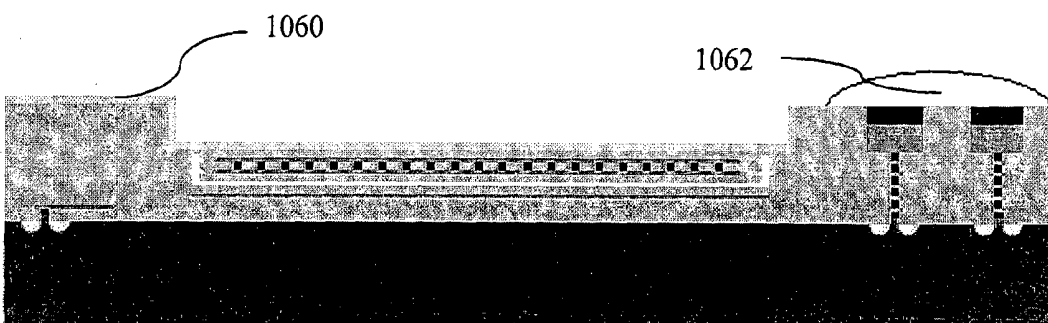


FIG. 10Z

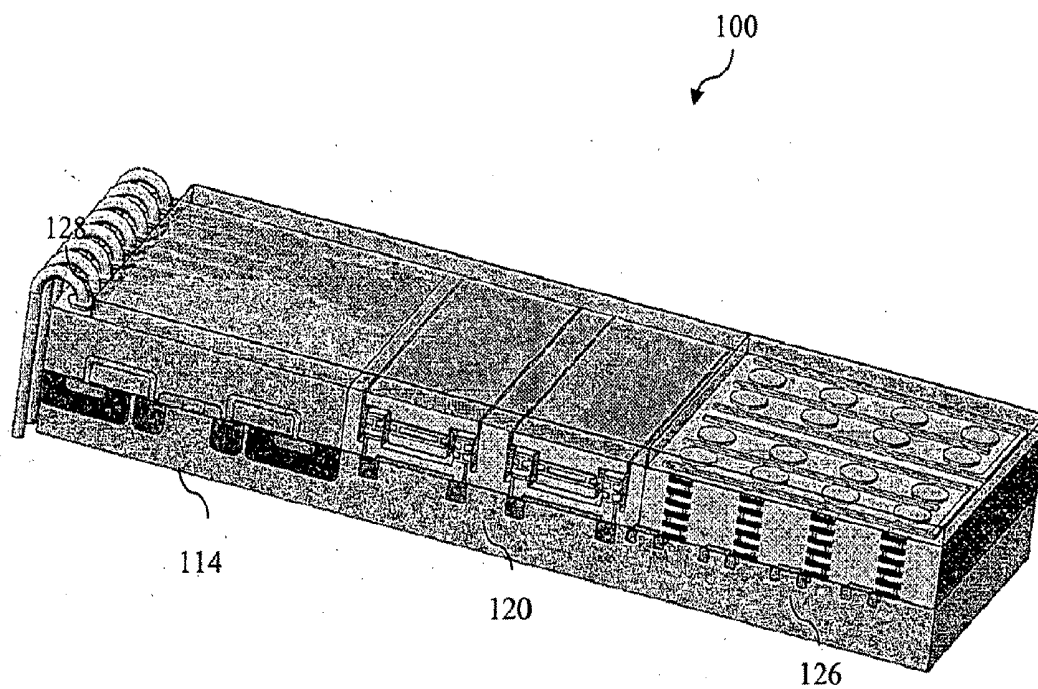


FIG. 11

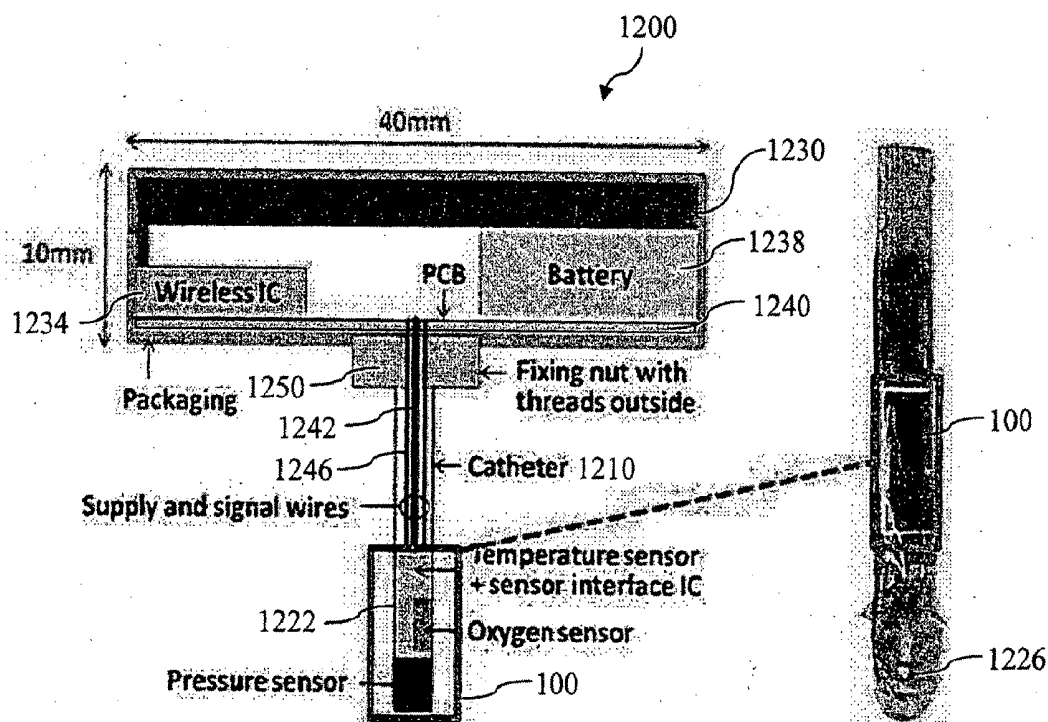


FIG. 12A

FIG. 12B

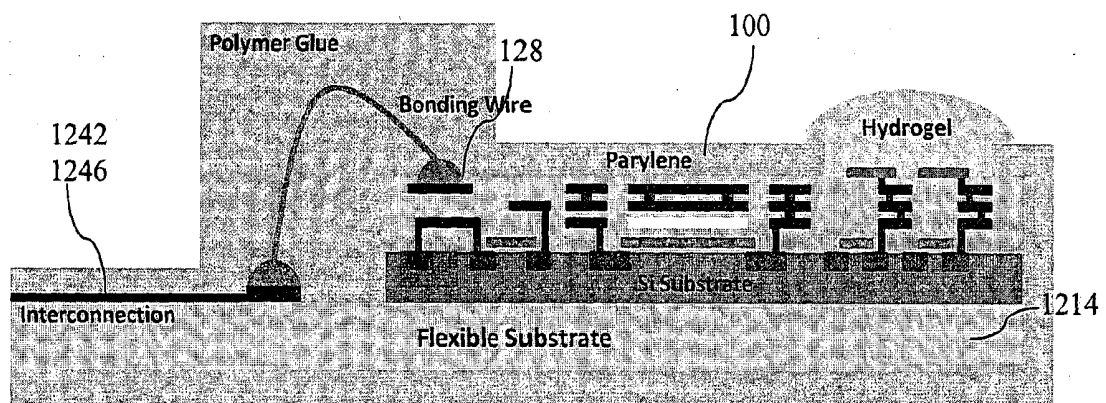


FIG. 12C

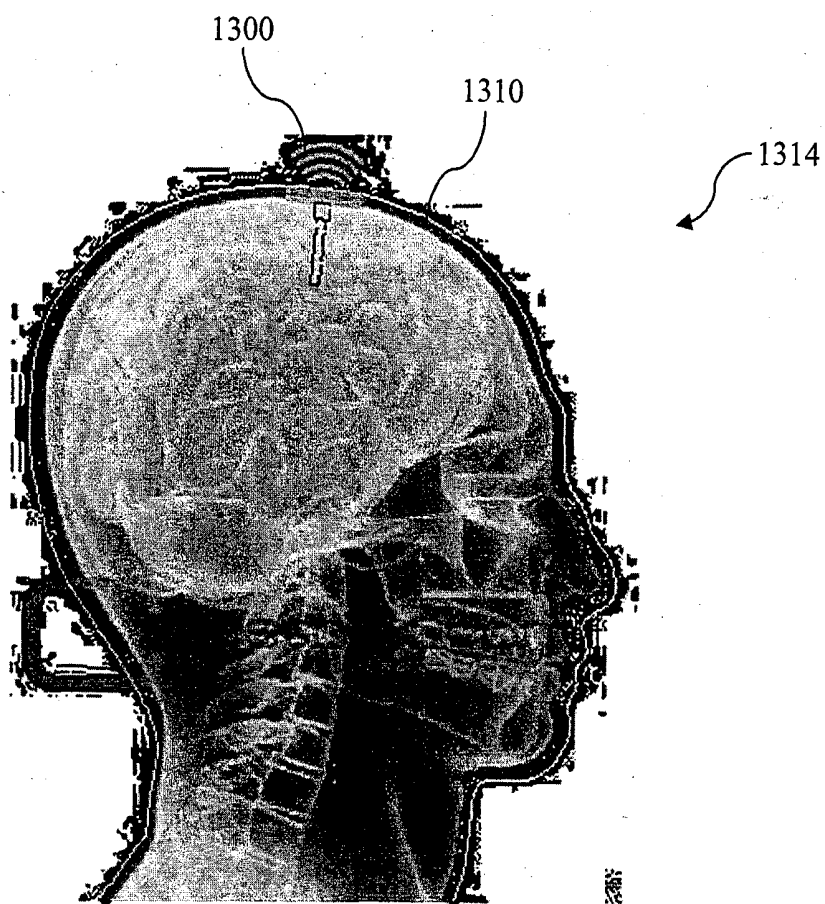


FIG. 13

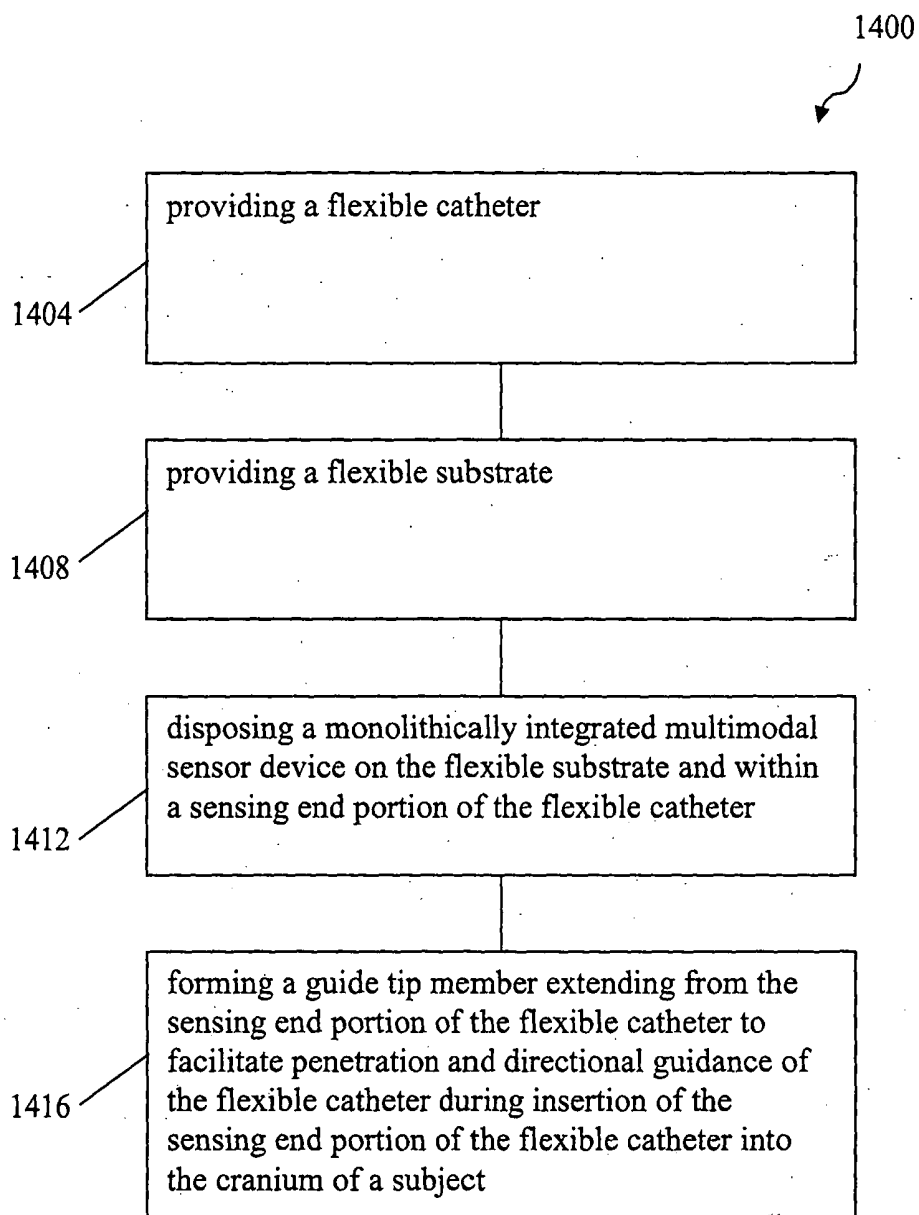


FIG. 14

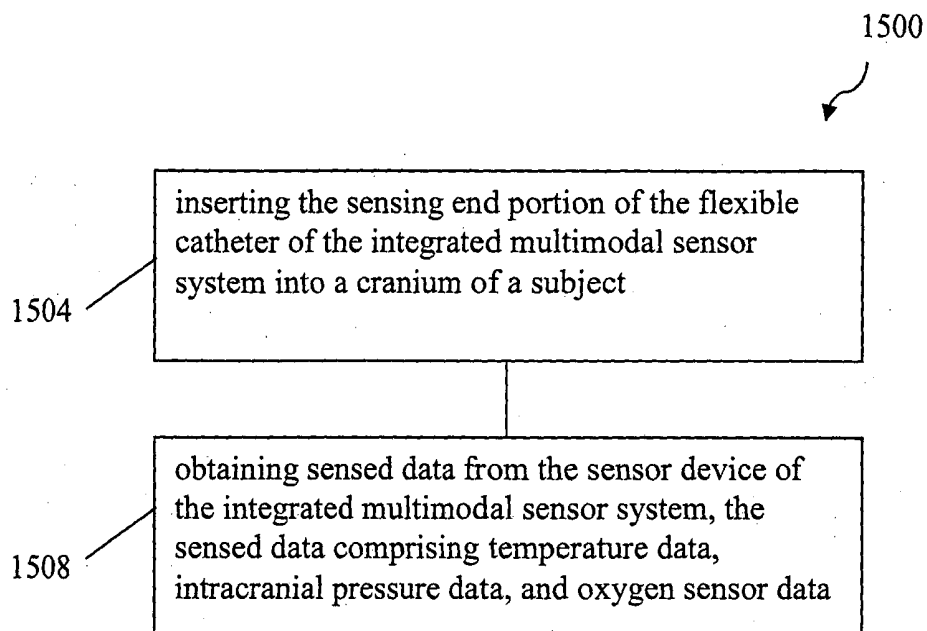


FIG. 15

INTEGRATED MULTIMODAL SENSOR DEVICE FOR INTRACRANIAL NEUROMONITORING

FIELD OF INVENTION

[0001] The present invention generally relates to an integrated multimodal sensor device for intracranial neuromonitoring, a multimodal sensor system for intracranial neuromonitoring comprising the integrated multimodal sensor device, and methods of fabrication thereof.

BACKGROUND

[0002] Traumatic brain injury (TBI) is a worldwide phenomenon that has devastating consequences to the patients and the society. The key to TBI management is the capability to control the intracranial pressure (ICP) through accurate monitoring the intracranial pressure, brain oxygenation, and brain temperature in the critical period. Any sudden increase in ICP have to be released either through the drainage of the excess cerebrospinal fluid or by chemotherapy. In a conventional TBI management, standalone pressure sensors, oxygen sensors, and temperature sensors in forms of miniaturized catheters are widely used in intensive care units. An external bolt system is typically used to attach the sensors to the skull to grasp the implanted catheters firmly in the patient's head. Custom data acquisition equipment may then be connected to the catheters directly through the bolt system for signal processing and real-time display of the sensed data from the sensors.

[0003] Practically, with the above-described approach, the inserted bolt size (thus the burr hole size) cannot be made small as it has to hold the 3 implanted catheters, and this extra space is more susceptible to bleeding and infection. Furthermore, the individual catheters are configured as a sensing device only, therefore signal conditioning and processing are done entirely by the external equipment.

[0004] A need therefore exists to provide a sensor device for intracranial neuromonitoring which seeks to overcome, or at least ameliorate, one or more of the deficiencies of the conventional art mentioned above. It is against this background that the present invention has been developed.

SUMMARY

[0005] According to a first aspect of the present invention, there is provided a monolithically integrated multimodal sensor device for intracranial neuromonitoring, the sensor device comprising:

- [0006] a single substrate;
- [0007] a temperature sensor formed on a first portion of the single substrate for detecting temperature;
- [0008] a pressure sensor formed on a second portion of the single substrate for detecting intracranial pressure; and
- [0009] an oxygen sensor formed on a third portion of the single substrate for detecting oxygen concentration,
- [0010] wherein sensing portions of the temperature sensor, the oxygen sensor and the pressure sensor, respectively, are formed at different layers of the sensor device.
- [0011] Preferably, the sensing portion of the temperature sensor is formed at the single substrate, the sensing portion of the pressure sensor is formed at intra-metal layers of the sensor device, and the sensing portion of the oxygen sensor is formed at a top metal layer of the sensor device.

[0012] Preferably, the temperature sensor comprises one or more transistors, and the sensing portion of the temperature sensor includes an active region of the respective one or more transistors.

[0013] Preferably, the transistor is a parasitic vertical PNP transistor.

[0014] Preferably, the pressure sensor comprises one or more capacitive MEMS pressure sensors, and the sensing portion of the pressure sensor includes a movable electrode of the respective one or more capacitive MEMS pressure sensors.

[0015] Preferably, the oxygen sensor comprises a switchable array of oxygen sensor elements, and the sensing portion of the oxygen sensor comprises a working electrode of the respective oxygen sensor elements.

[0016] Preferably, the oxygen sensor is configured to switch to one of the oxygen sensor elements to provide the oxygen level reading which satisfies a predetermined sensitivity level.

[0017] Preferably, the sensor device further comprises one or more application-specific integrated circuits formed on the single substrate for processing readings from the temperature sensor, the oxygen sensor, and the oxygen sensor.

[0018] According to a second aspect of the present invention, there is provided a method of fabricating a monolithically integrated multimodal sensor device for intracranial neuromonitoring, the method comprising:

- [0019] providing a single substrate;
- [0020] forming a temperature sensor on a first portion of the single substrate for detecting temperature;
- [0021] forming a pressure sensor on a second portion of the single substrate for detecting intracranial pressure; and
- [0022] forming an oxygen sensor on a third portion of the single substrate for detecting oxygen concentration,
- [0023] wherein sensing portions of the temperature sensor, the oxygen sensor and the pressure sensor, respectively, are formed at different layers of the sensor device.

[0024] Preferably, the sensing portion of the temperature sensor is formed at the single substrate, the sensing portion of the pressure sensor is formed at intra-metal layers of the sensor device, and the sensing portion of the oxygen sensor is formed at a top metal layer of the sensor device.

[0025] Preferably, the temperature sensor comprises one or more transistors, and the sensing portion of the temperature sensor includes an active region of the respective one or more transistors.

[0026] Preferably, the transistor is a parasitic vertical PNP transistor.

[0027] Preferably, the pressure sensor comprises one or more capacitive MEMS pressure sensors, and the sensing portion of the pressure sensor includes a movable electrode of the respective one or more capacitive MEMS pressure sensors.

[0028] Preferably, the oxygen sensor comprises a switchable array of oxygen sensor elements, and the sensing portion of the oxygen sensor comprises a working electrode of the respective oxygen sensor elements.

[0029] Preferably, the oxygen sensor is configured to switch to one of the oxygen sensor elements to provide the oxygen level reading which satisfies a predetermined sensitivity level.

[0030] Preferably, the method further comprises forming one or more application-specific integrated circuits on the

single substrate for processing readings from the temperature sensor, the oxygen sensor, and the oxygen sensor.

[0031] According to a third aspect of the present invention, there is provided an integrated multimodal sensor system for intracranial neuromonitoring, the sensor system comprising:

[0032] a flexible catheter;

[0033] a flexible substrate;

[0034] a monolithically integrated multimodal sensor device according to the above-described first aspect of the present invention disposed on the flexible substrate and within a sensing end portion of the flexible catheter; and

[0035] a guide tip member extending from the sensing end portion of the flexible catheter to facilitate penetration and directional guidance of the flexible catheter during insertion of the sensing end portion of the flexible catheter into the cranium.

[0036] Preferably, the guide tip member has a rounded tip and is made of silicone.

[0037] Preferably, the sensor system further comprises a housing including therein a wireless communication module for receiving sensed data from the sensor device and an antenna for transmitting the sensed data wirelessly to one or more remote extracranial devices.

[0038] According to a fourth aspect of the present invention, there is provided a method of forming an integrated multimodal sensor system for intracranial neuromonitoring, the method comprising:

[0039] providing a flexible catheter;

[0040] providing a flexible substrate;

[0041] disposing a monolithically integrated multimodal sensor device according to the above-described first aspect of the present invention on the flexible substrate and within a sensing end portion of the flexible catheter; and

[0042] forming a guide tip member extending from the sensing end portion of the flexible catheter to facilitate penetration and directional guidance of the flexible catheter during insertion of the sensing end portion of the flexible catheter into the cranium.

BRIEF DESCRIPTION OF THE DRAWINGS

[0043] Embodiments of the present invention will be better understood and readily apparent to one of ordinary skill in the art from the following written description, by way of example only, and in conjunction with the drawings, in which:

[0044] FIG. 1A depicts a schematic top view of an example monolithically integrated multimodal sensor device for intracranial neuromonitoring according to an example embodiment of the present invention;

[0045] FIG. 1B depicts a schematic cross-sectional view of the example sensor device shown in FIG. 1A;

[0046] FIG. 2 depicts a schematic diagram of an example temperature sensor circuit according to an embodiment of the present invention;

[0047] FIG. 3A depicts a cross-sectional view of one example capacitive MEMS pressure sensor according to an embodiment of the present invention;

[0048] FIGS. 3B and 3C depict the top view and the cross-sectional view of the released membrane of the pressure sensor captured in the scanning electro-microphotograph (SEM), respectively;

[0049] FIG. 4 depicts an exemplary the oxygen sensor configured as a 3-electrode system according to an embodiment of the present invention;

[0050] FIG. 5 depicts a schematic diagram of an exemplary ASIC integrally formed on the substrate according to an embodiment of the present invention;

[0051] FIG. 6A depicts a graph showing the output response of the pressure sensor versus the pressure applied in an experiment;

[0052] FIG. 6B depicts a graph showing the measured result of pressure sensor capacitance mismatch calibration;

[0053] FIG. 7A depicts a graph showing the output response of the oxygen sensor versus dissolved oxygen concentration in an experiment;

[0054] FIG. 7B depicts a graph showing the measured transient response of the oxygen sensor in an aqueous solution from nitrogen-saturated condition to air-saturated condition;

[0055] FIG. 8A depicts a graph illustrating the linear output response of the temperature sensor in an experiment;

[0056] FIG. 8B depicts a graph illustrating the temperature inaccuracy of multiple temperature sensors over the temperature range from -5°C. to 45°C. in an experiment;

[0057] FIG. 9 depicts an overview of a method of fabricating the monolithically integrated multimodal sensor device for intracranial neuromonitoring according to an embodiment of the present invention;

[0058] FIGS. 10A to 10Z shows the steps in fabricating the integrated multimodal sensor device according to an example embodiment of the present invention;

[0059] FIG. 11 an example completed sensor device (or sensor chip) fabricated according to an example embodiment of the present invention;

[0060] FIGS. 12A to 12C depict the sensor device packaged for in-vivo application (an integrated multimodal sensor system) according to an example embodiment of the present invention;

[0061] FIG. 13 depicts an example of the sensor system being used for in-vivo application;

[0062] FIG. 14 depicts an overview of a method of fabricating the sensor system for intracranial neuromonitoring according to an embodiment of the present invention; and

[0063] FIG. 15 depicts an overview of a method of intracranial neuromonitoring using the integrated multimodal sensor system for in-vivo application according to an embodiment of the present invention.

DETAILED DESCRIPTION

[0064] Intracranial neuromonitoring of various physiologic parameters is critical in neurological disorders such as traumatic brain injury (TBI), hydrocephalus and tumours that can cause changes in the pressure within the skull of a subject. Example embodiments of the present invention provide a monolithically integrated multimodal sensor device for intracranial neuromonitoring, including a temperature sensor for detecting intracranial temperature, a pressure sensor for detecting intracranial pressure, and an oxygen sensor for detecting oxygen concentration. In particular, in the example embodiments, the temperature sensor, the pressure sensor, and the oxygen sensor are integrated on a single substrate. This advantageously enables the sensor device having intracranial temperature, intracranial pressure and oxygen concentration sensing capabilities to be provided with a single catheter, thus eliminating the need to provide multiple catheters for obtaining multiple physiologic parameters. As a result, the

size of the bolt or burr hole required to perform intracranial neuromonitoring can be minimised, thus making it less susceptible to bleeding and infection. The overall intracranial neuromonitoring process is also greatly simplified since, for example, less catheters are involved.

[0065] FIG. 1A depicts a schematic top view of an example monolithically integrated multimodal sensor device **100** for intracranial neuromonitoring according to an example embodiment of the present invention. FIG. 1B depicts a schematic cross-sectional view of the example sensor device **100**. As shown, the sensor device **100** comprises a single substrate (preferably, silicon substrate) **110**, a temperature sensor **114** formed on a first portion **116** of the single substrate **110** for detecting intracranial temperature, a pressure sensor **120** formed on a second portion **122** of the single substrate **110** for detecting intracranial pressure, and an oxygen sensor **126** formed on a third portion **128** of the single substrate **110** for detecting oxygen concentration. In particular, sensing portions **130**, **132**, **134** of the temperature sensor **114**, the pressure sensor **120** and the oxygen sensor **126**, respectively, are formed at different layers of the sensor device **100**.

[0066] In the example embodiment as shown in FIG. 1B, the sensing portion **130** of the temperature sensor **114** is formed at the single substrate **110**, the sensing portion **132** of the pressure sensor **120** is formed at intra-metal layers **138** of the sensor device **100**, and the sensing portion **134** of the oxygen sensor **126** is formed at a top metal layer **142** of the sensor device **100**. In this regard, forming the sensing portions **130**, **132**, **134** of the three sensors **114**, **120**, **126** at different layers of the sensor device **100** enables the three sensors **114**, **120**, **126** to be formed integrally on a single substrate **110** (i.e., integrated into a single chip) using a customized integrated fabrication flow. The steps in fabricating the integrated multimodal sensor device **100** will be described in detail later below with reference to FIGS. **10A** to **10Z**.

[0067] In an example embodiment, the temperature sensor **114** is realised by one or more transistors, preferably, parasitic vertical PNP transistors. As an example, FIG. 2 shows a schematic diagram of an example temperature sensor circuit **200** which includes a PTAT (Proportional To Absolute Temperature) current generator **204**, a bandgap reference **208** and a V_{BE} amplifier **212**. In the PTAT current generator **204**, two identical PNP transistors Q_1 **230** and Q_2 **232** are biased in a current ratio of 1 to 5. The difference of the base emitter voltage V_{BE1} **234** and V_{BE2} **236** is a PTAT voltage ΔV_{BE} **238** which can be sensed by resistor R_1 **240** and feedback to the chopper stabilized error amplifier A_1 **242**. The current ratio of 1 to 5 is implemented by randomly scrambling the PMOS current sink **243** through dynamic element matching (DEM). As a result, the impact of the device mismatch to the circuit operation point is minimized, and the current flowing through the resistor R_1 **240** is a PTAT current I_p **244**. This PTAT current source **244** is mirrored to bias a NPN transistor Q_3 **246** having an identical size as transistors Q_1 **230** and Q_2 **232**, and produces a PTAT voltage drop across the resistor R_2 **248**. The bandgap voltage V_{BG} **250** is obtained by summing the base-emitter voltage V_{BE3} **252** and the PTAT voltage across R_2 **248**. The process spread of the saturation current, the finite value of the forward current gain, and the base resistance of transistor Q_3 **246** all contribute to base emitter voltage V_{BE3} **252** mismatch. In a preferred embodiment, a one-point calibration is implemented to compensate the V_{BE3} **252** mismatch. A 5-bit on-chip resistor trimming network including resistors (R_{t1} ,

t_{32}) **260** and switches (SK_{t1-t32}) **262** is used to provide coarse V_{BE3} calibration with 32 steps of PTAT voltage tuning at room temperature.

[0068] In the example embodiment, the sensing portion **130** of the temperature sensor **114** includes an active region of the respective one or more transistors. Preferably, the transistors are fabricated in the silicon substrate **110** by CMOS foundries and the operation of a PNP transistor can be expressed by the following Equation:

$$I_c = I_s \exp\left(\frac{V_{BE}}{V_T}\right) \quad (1)$$

where I_s is the saturation current, V_{BE} is the base emitter voltage, V_T is the thermal voltage, and I_c is the collector current of the bipolar transistor. As can be seen from Equation 1, the saturation current (I_s) has a strong temperature dependency, and the temperature sensor **114** has been found to exhibit a temperature sensitivity of about $-2 \text{ mV}/^\circ \text{C}$. with respect to V_{BE} .

[0069] However, fabrication mismatch may exist in standard CMOS process, and it has been found that the model as shown in Equation 1 is only good as long as the process parameters such as the saturation current (I_s) are well controlled. But the limited current gain associated with the PNP transistor, the finite value of the base resistance, the high level injection, and the Early effect all affect the accuracy and the sensitivity of the temperature sensor **114**. Therefore, in a preferred embodiment, V_{BE} calibration is implemented to improve the accuracy of the temperature sensor **114** as for example described above with reference to FIG. 2 where resistor trimming is the chosen technique to achieve the V_{BE} calibration. Various trimming circuit implementations have been disclosed in the art to address temperature sensor mismatches and yield good accuracies. Therefore, the present invention is not limited to the trimming circuit as shown in FIG. 2 and a person skilled in the art would be able to apply any other appropriate trimming circuit known in the art to the temperature sensor **114** to improve sensing accuracy. The steps in fabricating the temperature sensor **114** will be described in detail later below as part of the process of fabricating the integrated multimodal sensor device **100**.

[0070] In an example embodiment, the pressure sensor **120** is realised by one or more capacitive MEMS pressure sensors in CMOS. A cross-sectional view of one example capacitive MEMS pressure sensor **300** is schematically illustrated in FIG. 3A. The pressure sensor **300** is advantageously simple as it involves a front side release only. In the example embodiment, the MEMS configuration utilizes two metals layers **314**, **315** (M4 and M5) and three intra-metal dielectric layers **310**, **311**, **312** (IMD3, IMD4, and IMD5) (e.g., SiO_2) for the movable electrode **318**, and one metal layer **326** (M2) and two intra-metal dielectric layers **327** (IMD2 and IMD1) for the stationary electrode **322** under the movable electrode **318**. In order to create room for the movable electrode **318**, a first via **330**, a second via **334** and a third via **338** have to be etched away first and subsequently the intra-metal layer under the movable electrode **318** (i.e., M3 to form a cavity **350**). In this example, the sensing portion **132** of the pressure sensor **120** includes the movable electrode **318** of the respective one or more capacitive MEMS pressure sensors. For example, the etchant involved is a mixture of $\text{H}_2\text{SO}_4 + \text{H}_2\text{O}_2$ (2:1) heated at 100°C . over 120 minutes. The steps in fabricating the pres-

sure sensor 300 will be described in detail later below as part of the process of fabricating the integrated multimodal sensor device 100.

[0071] The top view and the cross-sectional view of the released membrane are captured in the scanning electro-microphotograph (SEM) and illustrated in FIGS. 3B and 3C, respectively. In FIG. 3C, the existence of the cavity 350 can be observed (which is shown in a dark shading) between the top plate 354 and the bottom plate 358. It can also be observed that the non-etched via 362 (which is shown in a light shading) connecting metal layer M4 314 and metal layer M5 315 within the top plate 354. The movable electrode 318 is formed using metal layers M4 314 and M5 315 and the vias 45 334 have two functions depending on the layout location. A first function is to serve as a path to release the structure (that is, to etch away the materials that metals layers and vias are made of, for example, Aluminium (Al) and Tungsten (W), respectively) and a second function is to connect M4 314 and M5 314 layers. As a final step, a protective polymer coating material 150 (preferably, Parylene-C) is patterned to encapsulate the pressure sensor's active area 132 using standard lithograph. In an example implementation, the MEMS pressure sensor 120 is configured as an array of 9 capacitors with a trimming circuit to achieve good accuracy and sensitivity. Various trimming circuit implementations have been disclosed to address pressure sensor mismatches and yield good accuracies. A person skilled in the art would be able to apply an appropriate trimming circuit known in the art to the pressure sensor 120 to improve sensing accuracy and thus it is not necessary to be described herein.

[0072] In an embodiment, the oxygen sensor 126 comprises a switchable array of oxygen sensor elements 410. A top view of oxygen sensor 126 in CMOS made up of an array of 16 oxygen sensor elements 410 is illustrated in FIG. 4. Preferably, the oxygen sensor elements 410 are Clark-type dissolved oxygen sensors. FIG. 4 illustrates the oxygen sensor 126 configured as a 3-electrode system (i.e., working electrode 410, counter electrode 414, and reference electrode 418). It will be appreciated that the oxygen sensor 126 of the present invention is not limited to a 3-electrode system. For example, the oxygen sensor 126 may be configured as a 2-electrode system (i.e., working electrode and reference electrode). In this embodiment, the sensing portion 134 of the oxygen sensor 126 comprises the oxygen sensor elements (working electrode) 410.

[0073] In an example embodiment, to fabricate the working electrode 410 on the top metal layer 142 of the sensor device 100, platinum is used as the raw material to form the working electrode 410. The working electrode 410 can be attached to the CMOS top metal layer 142 (e.g., aluminium) through a layer of 20 nm thick titanium in between the platinum working electrode 410 and the top metal layer 142. The actual physical shape of the working electrode 410 as shown in FIG. 4 can be patterned by E-beam evaporator together with lift-off. To maximize the working electrode 410 sensitivity, the following Equation can be used to relate the sensitivity with the area of working electrode 410:

$$i = \frac{nA_s F D C_{DO}}{\delta} \quad (2)$$

where n is the number of exchanged electrons, A_s is the area of the working electrode 410, F is Faraday's constant, D is the

diffusivity, C_{DO} is the dissolved oxygen concentration in a given sample, δ is the thickness of the selective permeable membrane, and i is the reduction current. By way of example only, the unit size of 25 $\mu\text{m} \times 50 \mu\text{m}$ working electrode 410, approximately 250 pA reduction current can be generated for every mmHg dissolved oxygen at room temperature.

[0074] In an embodiment, specific polymers 154, whose physical structures are selective permeable, are used to encapsulate the oxygen sensor 126. For instance, a nickel-salen polymer can be used as a solid electrolyte, and this polymer was found to be able to increase the sensitivity of the platinum working electrode 410. On the other hand, NAFION which is commercially available can be chosen as a solid electrolyte. NAFION has been used as a solid electrolyte which permits oxygen transport across its structure. Unfortunately, NAFION deposition on the platinum electrode 410 cannot be done using similar CMOS processing. Instead, it is usually deposited in drop-cast which is subjected to coating thickness mismatch.

[0075] All the sensors 114, 120, 126 fabricated in the sensor device 100 are calibrated to achieve a certain degree of accuracy. For instance, the specifications of both the pressure sensor 120 and the oxygen sensor 126 are configured to achieve an inaccuracy of ± 1 mmHg whereas the temperature sensor 114 is $\pm 0.2^\circ \text{C}$. for the typical sensing range. Due to the post-processing mismatch, the fabricated sensors suffer a certain degree of mismatch relative to its operating parameters. In the capacitive MEMS pressure sensor 120 or the PNP-based temperature sensor 114, sensor mismatches are relatively well modelled. As mentioned hereinbefore, various trimming circuit implementations have been disclosed to address pressure sensor and temperature sensor mismatches and yield good accuracies. Therefore, a person skilled in the art would be able to apply appropriate trimming circuits known in the art to the temperature sensor 114 and the pressure sensor 120 to improve sensing accuracy.

[0076] But on the other hand, the challenge in calibrating the electrochemical oxygen sensor 126 comes from the non-standard fabrication of the oxygen sensor 126. Specifically, the non-standard fabrication in developing the oxygen sensor 126 is the hydrogel 154 deposition, for example, the deposition of NAFION by drop-cast as mentioned above. The coating thickness of this hydrogel 154 is highly subjected to mismatch which is a significant factor resulting in the inaccuracy of the oxygen sensors 126. In the example embodiment, the oxygen sensor 126 is configured with sensor calibration. In particular, the oxygen sensor 126 comprises a switchable array of oxygen sensor elements 410 is provided to address the above problem. For example, the oxygen sensor 126 comprises 16 switchable working electrodes 410 sharing a common electrode 418 and a reference electrode 414 as illustrated in FIG. 4. In particular, the oxygen sensor 126 is configured to switch to one of the oxygen sensor elements 410 to provide the oxygen level reading which satisfies a predetermined sensitivity level. The specific working electrode element 410 can be activated by evaluating its sensitivity during the sensor calibration procedure. Therefore, the sensitivity of working electrode 410 can be recorded and evaluated against the target sensitivity. If there are more than a single working electrode 410 which can achieve the target sensitivity, the array implementation adds a back up to the system such that any specific sensor failure can be replaced by an available working electrode element 410.

[0077] In an embodiment, the sensor device 100 further comprises one or more application-specific integrated circuits (ASIC) integrally formed on the single substrate 110 for processing readings from the temperature sensor, the pressure sensor, and the oxygen sensor. FIG. 5 depicts a schematic diagram of an exemplary ASIC 500 integrally formed on the single substrate 110. The ASIC 500 comprises a pressure sensor interface circuit 504 including a capacitance-to-voltage converter (CVC) for processing readings from the pressure sensor 120, an oxygen sensor interface circuit 508 including a potentiostat and a transimpedance amplifier (TIA) for processing readings from the oxygen sensor 126, and a temperature sensor interface circuit 512 including a bandgap reference and a proportional-to-absolute-temperature (PTAT) voltage generator for processing readings from the temperature sensor 114. In the example embodiment, since the pressure, oxygen and temperature signals have low-frequency variation, the outputs of the sensor interface circuits 504, 508, 512 can be multiplexed to share a single 10-bit SAR ADC (successive approximation analog-to-digital converter) 520 for signal digitization. A digital controller 524 is provided for converting the ADC 520 output to a serial bit stream for communicating with the external devices such as an external data logger.

[0078] In an experiment, the capacitive MEMS pressure sensor 120 is configured as a capacitance to voltage converter (CVC) for direct signal processing, and FIG. 6A shows the output response of the CVC versus the pressure applied. The linear fit curve has a coefficient of determination (R^2) of 0.9862, indicating good linear response of the sensor circuit and the measured sensitivity is 0.67 mV/mmHg. A 14-bit ADC is able to convert this sensitivity into the required resolution. FIG. 6B shows the measured result of pressure sensor capacitance mismatch calibration. It is demonstrated that by changing the resistive DAC trimming code with UP/DOWN control, the trimming circuit can cover a linear tuning range from -237.8 fF to $+239.9$ fF with 0.93-fF resolution.

[0079] In an experiment, the oxygen sensor 126 is configured as a potentiometer, which outputs a current directly proportional to the concentration of oxygen. The current generated is then further converted to a voltage by a transimpedance amplifier. FIG. 7A is a plot of the output response of the oxygen sensor versus dissolved oxygen concentration and summarizes the measured result of the oxygen sensor 126 performance. Over the measured partial pressure of dissolved oxygen from 10 to 55 mmHg, the linear fit curve has a R^2 of 0.9957 and the measured sensitivity is 0.78 mV/mmHg, which is equivalent to an input sensitivity of 194 pA/mmHg. FIG. 7B shows the measured transient response of the oxygen sensor 126 in an aqueous solution from nitrogen-saturated condition to air-saturated condition. FIG. 7B demonstrates the fast response of the oxygen sensor to the change of dissolved oxygen concentration. Again, a 14-bit ADC is able to convert this detected partial pressure of the dissolved oxygen in 1 mmHg resolution.

[0080] In an experiment, the temperature sensor 114 is incorporated in the classical bandgap topology where the output of interest is the base emitter voltage. As the typical sensitivity of the base emitter voltage is about -2 mV/ $^{\circ}$ C., the base emitter voltage is actually connected to a second stage with a gain of 5 to increase the the sensitivity to above 10 mV/ $^{\circ}$ C. In this temperature sensor characterization, 9 chips were evaluated. Since the temperature sensitivity is increased by design, the resolution requirement of the ADC can be

reduced from 14 bits to 10 bits. As shown in FIG. 8A, the temperature sensor 114 has a linear output response with R^2 of 0.9999, the measured output sensitivity is about 11 mV/ $^{\circ}$ C. when the measurement results of 9 chips are averaged. FIG. 8B illustrates that a temperature inaccuracy of $\pm 0.3^{\circ}$ C. is achieved over the temperature range from -5° C. to 45° C. In addition, FIG. 8B shows that after one-point calibration at 35° C., the inaccuracy of the sensors is bound within $\pm 0.2^{\circ}$ C. over the target temperature range of 30° C. to 45° C.

[0081] An overview of a method 900 of fabricating the monolithically integrated multimodal sensor device 100 for intracranial neuromonitoring will now be described according to an embodiment of the present invention with reference to FIG. 9. The method 900 comprises a step 904 of providing a single substrate 110 (such as a CMOS substrate), a step 908 of forming a temperature sensor 114 on a first portion 116 of the single substrate 110 for detecting temperature, a step 912 of forming a pressure sensor 120 on a second portion 122 of the single substrate 110 for detecting intracranial pressure, and a step 916 of forming an oxygen sensor 126 on a third portion 128 of the single substrate 110 for detecting oxygen concentration. In a preferred embodiment, steps 908, 912 and 916 are parallel processes (CMOS processes), followed by post-processing steps such as to release the pressure sensor 120 and to deposit the platinum working electrode 410 over the top metal layer 142 of the oxygen sensor 126. In particular, sensing portions 130, 132, 134 of the temperature sensor 114, the pressure sensor 120 and the oxygen sensor 126, respectively, are formed at different layers of the sensor device 100. In an embodiment, the sensing portion 130 of the temperature sensor 114 is formed at the single substrate 110, the sensing portion 132 of the pressure sensor 120 is formed at intra-metal layers 138 of the sensor device 100, and the sensing portion 134 of the oxygen sensor 126 is formed at a top metal layer 142 of the sensor device. In this regard, forming the sensing portions 130, 132, 134 of the three sensors 114, 120, 126 at different layers of the sensor device 100 enables the three sensors 114, 120, 126 to be formed integrally on a single substrate 110 (i.e., integrated into a single chip) using a customized integrated fabrication flow. The steps in fabricating the integrated multimodal sensor device 100 will now be described in further detail according to an example embodiment of the present invention.

[0082] In the example embodiment, the integrated multimodal sensor device 100 is manufactured based on CMOS fabrication process using a $0.18\text{ }\mu\text{m}$ technology of GLOBAL-FOUNDRIES INC. As a first step, a single piece of blank wafer/substrate (preferably, silicon substrate) 110 is provided as illustrated in FIG. 10A on which the temperature sensor 114, the pressure sensor 120, the oxygen sensor 126 and the associated ASIC 500 are to be formed. A thin layer of gate oxide is deposited to form the NMOS transistors for the temperature sensor 114, oxygen sensor 126 and the ASIC 500, and a polysilicon layer 1004 is formed and patterned as shown in FIG. 10A. Subsequently, as shown in FIG. 10B, an oxide layer 1006 is deposited on the substrate 110 and then patterned at portions 1008 where n+ dopants should be diffused or implanted. FIG. 10B. Then, as shown in FIG. 10C, the n+ regions 1010 of the transistors are formed in the substrate 110 and the oxide layer 1006 is removed. Subsequently, the ILD (interlayer dielectric) 1012 is deposited on the substrate 110 and patterned as shown in FIG. 10D, and the VIA1 1014 is deposited and subjected to CMP (chemical mechanical planarization) as shown in FIG. 10E. The METAL1 (M1)

layer **1016** is then deposited on the ILD layer **1012** and patterned as shown in FIG. **10F**.

[0083] Subsequently, the IMD1 (intra-metal dielectric) layer **1018** is deposited over the METAL1 layer **1016** and ILD layer **1012** and patterned as shown in FIG. **10G**, and the VIA12 **1020** is deposited and subjected to CMP as shown in FIG. **10H**. Then, the METAL2 layer **1022** is deposited over the IMD1 layer **1018** and patterned as shown in FIG. **10I**. This metal layer **1022** will be utilised to define the bottom/stationary electrode **322** of the pressure sensor **120**. Subsequently, the IMD2 (intra metal dielectric) layer **1024** is deposited over the METAL2 layer **1022** and the IMD1 layer **1018** and patterned as shown in FIG. **10J**, and the VIA23 **1026** is deposited and subjected to CMP as shown in FIG. **10K**. The METAL3 layer **1028** is then deposited on the IMD2 layer **1024** and patterned as shown in FIG. **10L**. This metal layer **1028** will be utilised to define the release layer of the pressure sensor **120** (i.e., to form the cavity **350** as shown in FIG. **3A**). Subsequently, the IMD3 **1030** is deposited over the METAL3 layer **1028** and patterned as shown in FIG. **10M**, and then the VIA34 **1032** is deposited and subjected to CMP as shown in FIG. **10N**. The METAL4 layer **1034** is then deposited on the IMD3 layer **1030** and patterned as shown in FIG. **10O**. This metal layer **1034** will be utilised to define the top/movable electrode **318** of the pressure sensor **120**. Subsequently, the IMD4 layer **1036** is deposited on the METAL4 layer **1034** and patterned as shown in FIG. **10P**, and then the VIA45 **1038** is deposited and subjected to CMP as shown in FIG. **10Q**. The METAL5 layer **1040** is then deposited on the IMD4 layer **1036** and patterned as shown in FIG. **10R**. This metal layer **1040** will also be utilised to define the top/movable electrode **318** of the pressure sensor **120**, connected in parallel with the METAL4 layer **1034**.

[0084] Subsequently, the IMD5 layer **1042** is deposited on the METAL5 layer **1040** and patterned as shown in FIG. **10S**, and then the VIA56 **1044** is deposited and subjected to CMP as shown in FIG. **10T**. The METAL6 layer **1046** (i.e., the top metal layer **142**) is then deposited on the IMD5 layer **1042** and patterned as shown in FIG. **10U**. This metal layer **1046** will be utilised to fabricate the electrodes **410** of the oxygen sensor **126**. Subsequently, a passivation oxide layer **1048** is deposited over the device and patterned as shown in FIG. **10V**. It will be appreciated that routing to/from and within the ASIC **500** can be done using any metal layer described above.

[0085] The CMOS wafer is now completed and the CMOS post-fabrication process will now be described. In order to ensure the CMOS compatibility, only low temperature post-process is used in the example embodiment. At this stage, the CMOS wafer have integrated thereon the temperature sensor **114**, the pressure sensor **120** (but the membrane not yet released), and the oxygen sensor **120** (but without the platinum working electrode **410** deposited yet). In the post-fabrication process, a first step is to etch the sacrificial stacked layer **1050** in order to release the suspended membrane **1052** as shown in FIG. **10W**. In order to etch the stacked metal (>99% Aluminium) and via (Tungsten) layers, a H₂SO₄+H₂O₂ solution is used to perform the release. During the etching of the sacrificial layer **1050**, the dielectric acts as stopping layer protecting top electrode **1040** and bottom electrode **1022**, electrical connections and IC, if required. After the release of the membrane **1052**, low stress oxide layer **1054** is deposited in order to seal the etching holes **1056** as shown in FIG. **10X**. The etching holes **1056** are sealed under a vacuum chamber, so the cavity **350** under the membrane **1052**

is nearly in vacuum (about 6 mTorr). Subsequently, using photolithography and RIE the oxide layer **1054** is patterned in order to expose the oxygen sensor **126**, and then Platinum **1058** is deposited on the top metal layer **1046** and patterned using a lift-off process to form the working electrodes **410** as shown in FIG. **10Y**. In addition, using photolithography and RIE, the oxide layer **1054** is patterned in order to expose the pads (not shown in FIG. **10Z**) to allow electrical connections. Once the CMOS-MEMS fabrication is finished, biocompatible packaging process is performed, including deposition and patterning of a protective polymer coating material (preferably Parylene) **1060** over the pressure sensor **120** and deposition of a polymer (preferably, hydrogel (NAFION)) **1062** to encapsulate the oxygen sensor **125** as shown in FIG. **10Z**.

[0086] FIG. **11** illustrates an example completed sensor device (or sensor chip) **100** fabricated according to the example embodiment of the present invention.

[0087] An embodiment of the present invention will now be described where the sensor device **100** is packaged for in-vivo application as illustrated in FIG. **12A** and FIG. **12B**. In particular, there is provided an integrated multimodal sensor system **1200** for intracranial neuromonitoring as schematically depicted in FIG. **12A** incorporating the sensor device **100**. The sensor system **1200** comprises a flexible catheter **1210**, a flexible substrate **1214**, a sensor device **100** disposed on the flexible substrate **1214** and within a sensing end portion **1222** of the flexible catheter **1210**, and a guide tip member **1226** extending from the sensing end portion **1222** of the flexible catheter **1210** to facilitate penetration and directional guidance of the flexible catheter **1210** during insertion of the sensing end portion **1222** of the flexible catheter **1210** into the skull/cranium **1310** of a subject **1314** as illustrated in FIG. **13**. In the example embodiment, the sensor device **100** is glued onto a flexible substrate **1214** (e.g., flexible PCB) which is biocompatible. The soft nature of the flexible substrate **1214** minimises the possibility of disrupting the tissue, but it has been found to suffer from directional guidance. Accordingly, in the example embodiment, the guide tip member **1226** is assembled adjacent the sensor device **100** to provide facilitate penetration and directional guidance of the flexible catheter **1210** into the skull **1310**. Preferably, the guide tip member **1226** has a rounded tip and is made of silicone.

[0088] In the example embodiment, the sensor system **1200** further comprises a housing **1230** including a wireless communication module **1234** for receiving sensed data from the sensor device **100** and an antenna module **1236** for transmitting the sensed data wirelessly to one or more remote extracranial devices (e.g., a computer which receives the transmitted data and stores and/or displays the received data). The housing **1230** may further comprise a power source **1238**, such as a battery, for powering the sensor system **1200**. The power source **1238** and the wireless communication module **1234** are installed on a PCB **1240** of the housing **1230**. As illustrated in FIG. **12A**, the flexible catheter **1218** has a power wire **1242** and a signal wire **1246** therein each extending between and connected to the sensor device **100** and the housing **1230** (i.e., the PCB **1240**). The power wire **1242** is arranged to supply power from the power source **1238** to the sensor device **100** and the signal wire **1246** is arranged to transmit the sensed data from the sensor device **100** to the wireless communication module **1234**. In this regard, the sensor device **100** comprises a plurality of contacts **128** (or I/O ports) which is configured to be bonded to the power wire **1242** and the signal wire **1246** in the sensor system **1200**. FIG.

12C illustrates the same sensor device 100 as FIG. 1B but the power wire 1242 and signal wire(s) 1246 connected to the contacts 128 via bonding wires (only one bonding wire is shown in FIG. 12C). By way of example only, there are 8 contacts 128 for connecting to 8 bonding wires. As can be appreciated from FIG. 11, the contacts 128 are advantageously arranged so as to allow single-side wirebonding.

[0089] The sensor system 1200 also comprises a fastener (e.g., bolt) 1250 formed on a bottom side of the housing 1230 for attaching the housing 1230 to the skull 1210 of the subject 1214, and thus supporting the flexible catheter 1210 and the sensor device 100 within the skull 1210 for intracranial neuromonitoring. As shown in FIG. 11A, the flexible catheter 1210 attached to and extending from the housing 1230 may run through a central hollow portion of the fastener 1250.

[0090] By way of example only, FIG. 12B illustrates a prototype of the flexible catheter 1210 with the sensor device 100 embedded therein, along with the guide tip member 1226 extending from the sensor device 100.

[0091] An overview of a method 1400 of fabricating the sensor system 1200 for intracranial neuromonitoring will now be described according to an embodiment of the present invention with reference to FIG. 14. The method 1400 comprises a step 1404 of providing a flexible catheter 1210, a step 1408 of providing a flexible substrate 1214, a step 1412 of disposing a sensor device 100 on the flexible substrate 1214 and within a sensing end portion 1222 of the flexible catheter 1210, and a step 1416 of forming a guide tip member 1226 extending from the sensing end portion 1222 of the flexible catheter 1210 to facilitate penetration and directional guidance of the flexible catheter 1210 during insertion of the sensing end portion 1222 of the flexible catheter 1210 into the cranium 1310 of a subject 1314.

[0092] An overview of a method 1500 of intracranial neuromonitoring using the integrated multimodal sensor system for in-vivo application will now be generally described with reference to FIG. 15. The method 1500 comprises a step 1504 of inserting the sensing end portion 1222 of the flexible catheter 1210 of the integrated multimodal sensor system 1200 into a cranium 1310 of a subject 1314 and a step 1508 of obtaining sensed data from the sensor device 100 of the integrated multimodal sensor system 1200, the sensed data comprising temperature data, intracranial pressure data, and oxygen sensor data.

[0093] Accordingly, example embodiments of the present invention described herein provide a monolithically integrated multimodal sensor device 100 for intracranial neuromonitoring, including a temperature sensor for detecting intracranial temperature, a pressure sensor for detecting intracranial pressure, and an oxygen sensor for detecting oxygen concentration. In particular, the temperature sensor, the pressure sensor, and the oxygen sensor are integrated on a single substrate. This advantageously enables the sensor device having intracranial temperature, intracranial pressure and oxygen concentration sensing capabilities to be provided with a single catheter, thus eliminating the need to provide multiple catheters for obtaining multiple physiologic parameters. In addition, the sensor device 100 can advantageously be fabricated in a CMOS-compatible process, thus reducing fabrication costs. The miniaturized size of the sensor device facilitates the integration of full intracranial neuromonitoring system 1200 in a single catheter 1210. As a result, the size of the bolt or burr hole required to perform intracranial neuromonitoring can be minimised, thus making it less suscep-

tible to bleeding and infection. The overall intracranial neuromonitoring process is also greatly simplified since, for example, less catheters are involved.

[0094] It will be appreciated by a person skilled in the art that numerous variations and/or modifications may be made to the present invention as shown in the specific embodiments without departing from the spirit or scope of the invention as broadly described. The present embodiments are, therefore, to be considered in all respects to be illustrative and not restrictive.

1. A monolithically integrated multimodal sensor device for intracranial neuromonitoring, the sensor device comprising:

- a single substrate;
 - a temperature sensor formed on a first portion of the single substrate for detecting temperature;
 - a pressure sensor formed on a second portion of the single substrate for detecting intracranial pressure; and
 - an oxygen sensor formed on a third portion of the single substrate for detecting oxygen concentration,
- wherein sensing portions of the temperature sensor, the oxygen sensor and the pressure sensor, respectively, are formed at different layers of the sensor device.

2. The sensor device according to claim 1, wherein the sensing portion of the temperature sensor is formed at the single substrate, the sensing portion of the pressure sensor is formed at intra-metal layers of the sensor device, and the sensing portion of the oxygen sensor is formed at a top metal layer of the sensor device.

3. The sensor device according to claim 1, wherein the temperature sensor comprises one or more transistors, and the sensing portion of the temperature sensor includes an active region of the respective one or more transistors.

4. The sensor device according to claim 3, wherein the transistor is a parasitic vertical PNP transistor.

5. The sensor device according to claim 1, wherein the pressure sensor comprises one or more capacitive MEMS pressure sensors, and the sensing portion of the pressure sensor includes a movable electrode of the respective one or more capacitive MEMS pressure sensors.

6. The sensor device according to claim 1, wherein the oxygen sensor comprises a switchable array of oxygen sensor elements, and the sensing portion of the oxygen sensor comprises a working electrode of the respective oxygen sensor elements.

7. The sensor device according to claim 6, wherein the oxygen sensor is configured to switch to one of the oxygen sensor elements to provide the oxygen level reading which satisfies a predetermined sensitivity level.

8. The sensor device according to claim 1, further comprises one or more application-specific integrated circuits formed on the single substrate for processing readings from the temperature sensor, the oxygen sensor, and the oxygen sensor.

9. A method of fabricating a monolithically integrated multimodal sensor device for intracranial neuromonitoring, the method comprising:

- providing a single substrate;
- forming a temperature sensor on a first portion of the single substrate for detecting temperature;
- forming a pressure sensor on a second portion of the single substrate for detecting intracranial pressure; and
- forming an oxygen sensor on a third portion of the single substrate for detecting oxygen concentration,

wherein sensing portions of the temperature sensor, the oxygen sensor and the pressure sensor, respectively, are formed at different layers of the sensor device.

10. The method according to claim 9, wherein the sensing portion of the temperature sensor is formed at the single substrate, the sensing portion of the pressure sensor is formed at intra-metal layers of the sensor device, and the sensing portion of the oxygen sensor is formed at a top metal layer of the sensor device.

11. The method according to claim 9, wherein the temperature sensor comprises one or more transistors, and the sensing portion of the temperature sensor includes an active region of the respective one or more transistors.

12. The method according to claim 11, wherein the transistor is a parasitic vertical PNP transistor.

13. The method according to claim 9, wherein the pressure sensor comprises one or more capacitive MEMS pressure sensors, and the sensing portion of the pressure sensor includes a movable electrode of the respective one or more capacitive MEMS pressure sensors.

14. The method according to claim 9, wherein the oxygen sensor comprises a switchable array of oxygen sensor elements, and the sensing portion of the oxygen sensor comprises a working electrode of the respective oxygen sensor elements.

15. The method according to claim 14, wherein the oxygen sensor is configured to switch to one of the oxygen sensor elements to provide the oxygen level reading which satisfies a predetermined sensitivity level.

16. The method according to claim 9, further comprises forming one or more application-specific integrated circuits on the single substrate for processing readings from the temperature sensor, the oxygen sensor, and the oxygen sensor.

17. An integrated multimodal sensor system for intracranial neuromonitoring, the sensor system comprising:

a flexible catheter;

a flexible substrate;

a monolithically integrated multimodal sensor device for intracranial neuromonitoring, the sensor device comprising:

a single substrate;

a temperature sensor formed on a first portion of the single substrate for detecting temperature;

a pressure sensor formed on a second portion of the single substrate for detecting intracranial pressure; and

an oxygen sensor formed on a third portion of the single substrate for detecting oxygen concentration,

wherein sensing portions of the temperature sensor, the oxygen sensor and the pressure sensor, respectively, are formed at different layers of the sensor device, wherein the monolithically integrated multimodal sensor device is disposed on the flexible substrate and within a sensing end portion of the flexible catheter; and

a guide tip member extending from the sensing end portion of the flexible catheter to facilitate penetration and directional guidance of the flexible catheter during insertion of the sensing end portion of the flexible catheter into the cranium.

18. The integrated multimodal sensor system according to claim 17, wherein the guide tip member has a rounded tip and is made of silicone.

19. The integrated multimodal sensor system according to claim 18, further comprising a housing including therein a wireless communication module for receiving sensed data from the sensor device and an antenna for transmitting the sensed data wirelessly to one or more remote extracranial devices.

20. A method of forming an integrated multimodal sensor system for intracranial neuromonitoring, the method comprising:

providing a flexible catheter;

providing a flexible substrate;

disposing a monolithically integrated multimodal sensor device for intracranial neuromonitoring on the flexible substrate and within a sensing end portion of the flexible catheter, wherein the sensor device comprises:

a single substrate;

a temperature sensor formed on a first portion of the single substrate for detecting temperature;

a pressure sensor formed on a second portion of the single substrate for detecting intracranial pressure; and

an oxygen sensor formed on a third portion of the single substrate for detecting oxygen concentration,

wherein sensing portions of the temperature sensor, the oxygen sensor and the pressure sensor, respectively, are formed at different layers of the sensor device; and

forming a guide tip member extending from the sensing end portion of the flexible catheter to facilitate penetration and directional guidance of the flexible catheter during insertion of the sensing end portion of the flexible catheter into the cranium.

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专利名称(译)	用于颅内神经监测的集成多模式传感器装置		
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摘要(译)

提供了一种用于颅内神经监测的单片集成多模式传感器装置，该传感器装置包括：单个基板；温度传感器，形成在单个基板的第一部分上，用于检测温度；压力传感器，形成在单个基板的第二部分上，用于检测颅内压；氧传感器形成在单个基板的第三部分上，用于检测氧浓度。特别地，分别感测温度传感器，氧传感器和压力传感器的部分形成在传感器装置的不同层处。还提供了一种集成的多模传感器系统，其包括传感器装置和相关的制造方法。

